



TO : DATE : June. 07. 2011

SAMSUNG TFT-LCD

MODEL NO. : LMS501KF03

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SA		ion Developme Mobile D i	ent Team 2 isplay Co., Lt	d.

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Revision History

Data		Rev. No.	Page			Sur	mmary	
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This Specification defines general provisions as well as inspection standards for LCD module supplied by SAMSUNG SMD Co., LTD., If the event of unforeseen problems or unspecified items occurs, we naturally shall negotiate and agree to solution with customer.

Warranty

Basically, warranty term is **15 months** of reliability characteristics of quality level after the outgoing date in SAMSUNG SMD Co., LTD., and SAMSUNG SMD Co., LTD., could compensate for defectives which happens within warranty term under condition that the products should be stored or be used as specified under normal condition within the contents of specification.

Otherwise, it is impossible to compensate for defectives when they happens by customer's mistake such as careless handing or circuit change, etc.

And after 15 months of warranty term, all replacements for defectives will be charged. This Specification stipulates the final and comprehensive requirements for the respective products hereof. Beyond this Specification, it is responsibility of the customer to explicitly disclose any additional requirements, information or reservations regarding these requirements to Samsung SMD prior to implementation, where any and all disclosures of the customer shall be with an authorized representative of Samsung SMD in writing.

Samsung SMD shall not be responsible for safety, performance, functionality, compatibility of the system with which the Samsung SMD-supplied components are integrated unless such features have been expressly communicated and described in the Specification.

SAMSUNG SMD MAKES NO GUARANTY OR WARRANTY, EXPRESS OR IMPLIED INCLUDING BUT NOT LIMITED TO MERCHANTABILITY OR FITNESS FOR A PARTICULAR PURPOSE, TO ANY PARTY.

Moreover, any party should do their own due diligence regarding these requirements prior to implementation.

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General Description

* Description

LMS501KF03 is a TMR(Transmissive with Micro Reflective) type color active matrix TFT (Thin Film Transistor) liquid crystal display (LCD) that uses amorphous silicon TFT as a switching devices. This model is composed of a TFT-LCD module, a driver circuit and a back-light unit.

The resolution of a 5.01" contains $480(xRGB) \times 800$ dots and can display 16.7M colors.

* Features

- Transmissive with Micro Reflective type and back-light with 12 LEDs
- mPVA(Normally black) mode.
- RGB 24bit Parallel + SPI
- Portrait type

* Applications

- Display terminals for PMP(Portable Multimedia Player), PND(Portable Navigation Display) application products.
- Display terminals for AV application products

* General information

Items	Specification	Unit	Note
Display area	65.52(H) x 109.2(V) (5.01" diagonal)	mm	-
Driver element	a-Si TFT active matrix	-	-
Display colors	16.7M	colors	-
Number of pixels	480 x RGB x 800	dot	-
Pixel arrangement	RGB Vertical Stripe	-	-
Pixel pitch	0.1365(H) x 0.1365(V)	mm	186ppi
Display mode	Normally black	-	-
Surface strength	Min. 3	Н	-

* Mechanical information

	Item	Min.	Тур.	Max.	Unit	Note
Madula	Horizontal(H)	71.20	71.40	71.60	mm	(1)
Module	Vertical(V)	120.20	120.40	120.60	mm	(1)
size	Thickness(T)	2.30	2.50	2.70	mm	(1)
,	Weight	-	45	54	g	-
ote (1) Include Back-light without FPC.						

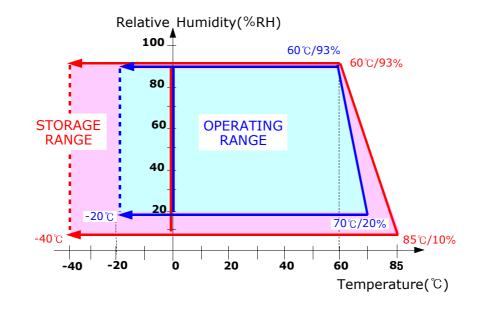
Refer to the Outline Dimension in Appendix.

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1. Absolute Maximum Ratings

1.1 Absolute Ratings of Environment

Item	Symbol	Min.	Max.	Unit	Note
Storage temperature	T _{STG}	-40	85	°C	(1)
Operating temperature (Ambient temperature)	T _{OPR}	-20	70	°C	(1),(2),(3)



- Note (1) 93 % RH Max. (40 °C ≥ Ta) Maximum wet-bulb temperature at 39 °C or less. (Ta > 40 °C) No condensation.
- Note (2) In case of below 0°, the response time of liquid crystal (LC) becomes slower and the color of panel becomes darker than normal one. Level of retardation depends on temperature, because of LC's characteristics.
- Note (3) If any fixed pattern is displayed on LCD for minutes, image-sticking phenomenon may occur.

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1.2 Electrical Absolute Ratings

(1) TFT-LCD	Module
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Item	Symbol	Min.	Max.	Unit	Note
Analog/Logic Voltage	VDD3	2.3	4.8	V	(1)
I/O Interface Voltage	VDD1	1.65	3.3	V	(1)

(2) Back-Light Unit

 $(Ta = 25 \pm 2^{\circ}C)$

Item	Symbol	Min.	Max.	Unit	Note
Current	\mathbf{I}_{LED}	-	25	mA	(2)

Note (1) When used out of the absolute maximum ratings, the LSI may be permanently damaged.

Note (2) Permanent damage to the device may occur if maximum values are exceeded or reverse voltage is loaded.

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 $(Ta = 25^{\circ}C)$

The following items are measured under stable conditions. The optical characteristics should be measured in a dark room or equivalent state with the methods shown in Note (1).

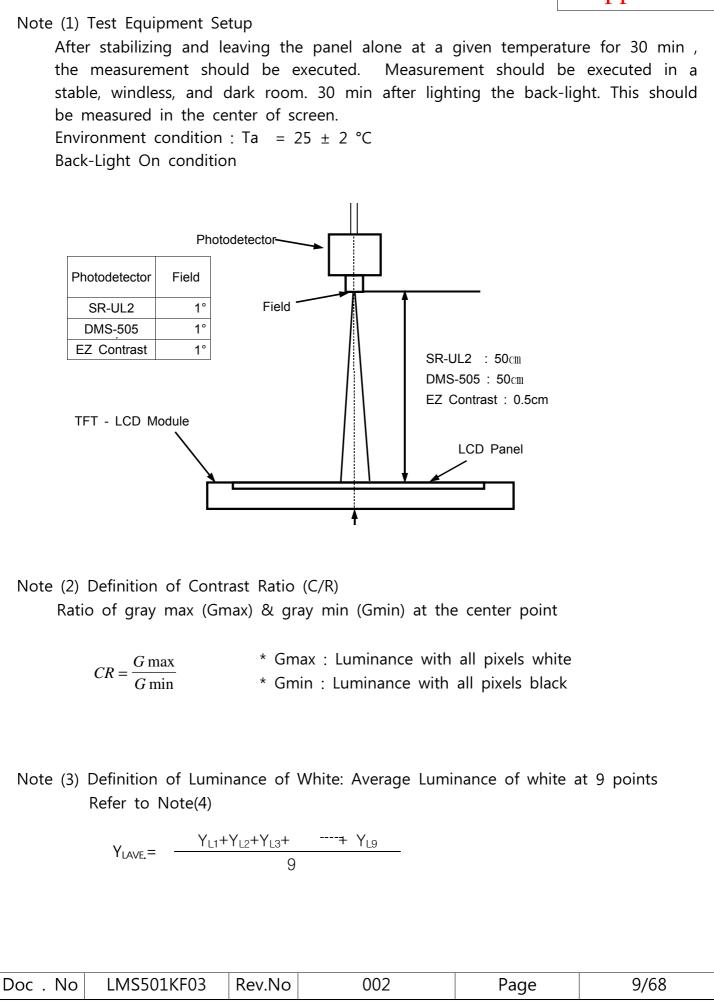
(Measuring equipment: SR-UL2, DMS-505, EZ CONTRAST)

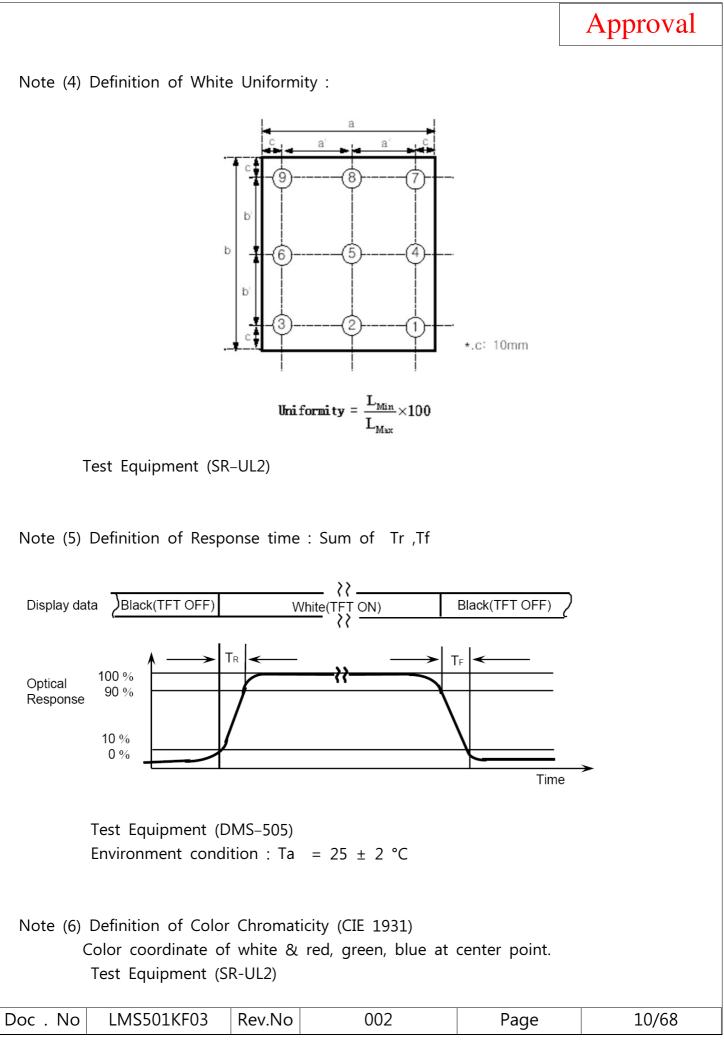
 $(Ta = 25 \pm 2^{\circ}C, VDD3 = 3.0V, f_{Frame} = 60Hz, I_{LED} = 18mA)$

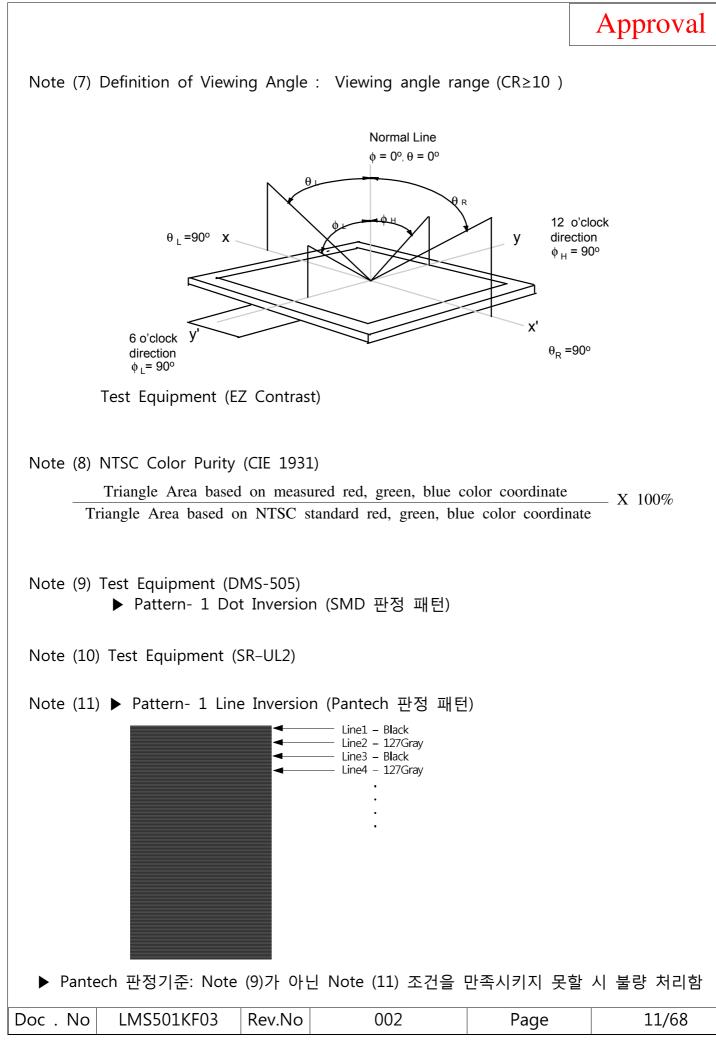
Iten	n	Symbo I	Condition	Min.	Тур.	Max.	Unit	Note
Contrast (Center		C/R		700	1000	-	-	(2)
Average Lu of White at		YLAVE.		400	500	-	cd/m2	(3),(4
Uniforr	nity			70	80		%	(3),(1
Flicke	or					-25	dB	(9)
FIICK	-		NOTE (1)			6.5	%	(11)
Crosst	alk		θ = 0			3	%	(10)
NTSC Colo (CIE 19	-		Φ = 0 Normal	45	50		%	(8)
Response time	Rising:Tr Falling:Tf	Tr+Tf	Viewing Angle	-	25	-	msec	(5)
	White	Wx	B/L On	0.259	0.309	0.359		
	vvince	Wy		0.285	0.335	0.385		
Color	Red	Rx		0.551	0.601	0.651	_	
Color chromaticity		Ry		0.310	0.360	0.410	_	(6)
(CIE 1931)	Green	Gx		0.276	0.326	0.376	-	(0)
		Gy		0.515	0.565	0.615	-	
	Blue	Bx		0.099	0.149	0.199	_	
		By		0.073	0.123	0.173		
	Hor.	θι		75	80	-		
Viewing		θ _R	C/R≥10	75	80	-	Degrees	(7)
angle	Ver.	Ф _Н	B/L On	75	80	-	-	
		Φ _L		75	80	-		











3. Electrical Characteristics

3.1 TFT-LCD Module

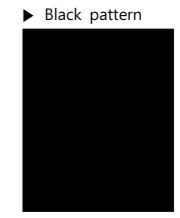
Ta = 25 ± 2°C

Item	Symbol	Min.	Тур.	Max.	Unit	Note
Power Supply voltage (analog)	VDD3	2.95	3.0	3.05	V	
I/O Logic Voltage	VDD1	1.75	1.8	1.85	V	
Power Supply current (logic)	IDD1		250	500	uA	w/o BLU, @ White,
Power Supply current(analog)	IDD3		50	60	mA	(1)
Sleep current (logic)	IDD1			10	uA	w/o BLU,
Sleep current (analog)	IDD3			100	uA	W/O DLO,
Frame frequency	f _{Frame}	-	60	-	Hz	-
Dot Clock	DOTCLK	-	24.576	-	MHz	-

Note (1) VDD3 = 3.0V, f_{Frame} = 60Hz, DOTCLK = 24.576MHz

(2) Dissipation current check pattern

▶ White pattern



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3.2 Back-Light unit

The Back-Light system is an edge-lighting type with 12(6+6) white LEDs (Light Emitting Diode).

(Ta=25	+	2°C)
(Ia-2)	<u> </u>	$Z \cup$

Item	Symbol	MIN.	TYP.	MAX.	Unit	Note
LEDs Current	\mathbf{I}_{B}	-	18	25	mA	(1),(2)
Power Consumption	P _{BL}	-	0.66	1.0	W	(2),(3)

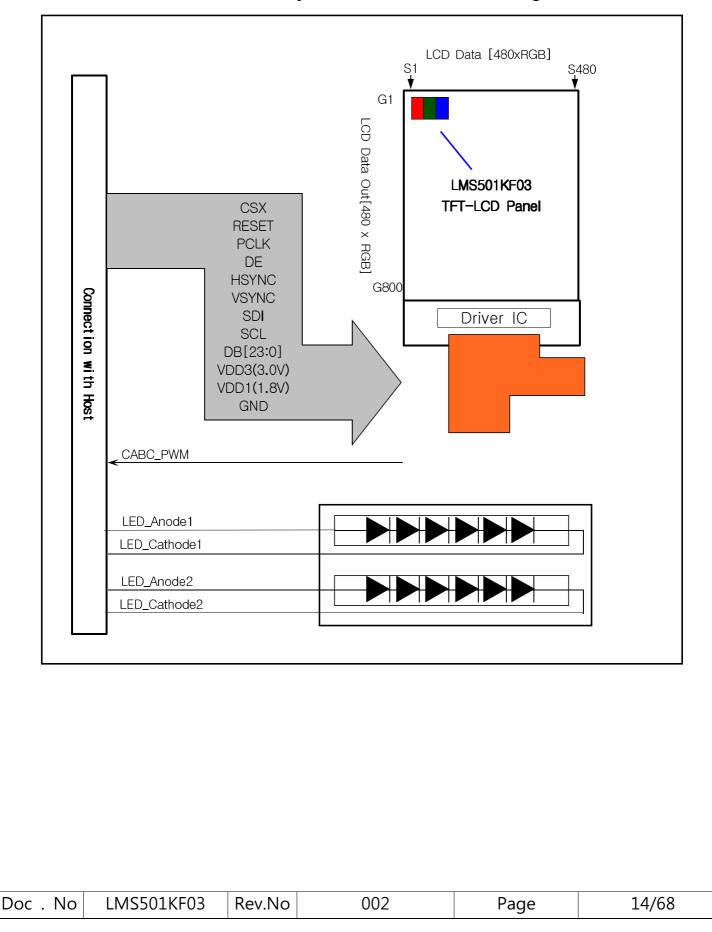
Note (1) The LEDs parallel type (6LEDs x 2)

- (2) Where $I_B = (18)mA$, $V_B = P_{BL} / I_B$ per 1 LEDs string
- (3) DC current(voltage) use only.

If PWM(pulse width modulation) used, some problems may be happened.

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4. Block Diagram



4-1. TFT-LCD Module (Interface System Structure) with Back Light Unit

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5. Input Terminal Pin Assignment

5.1 Input Signal & Power (*.Connector : Hirose, FH26-51S-0.3SHW)

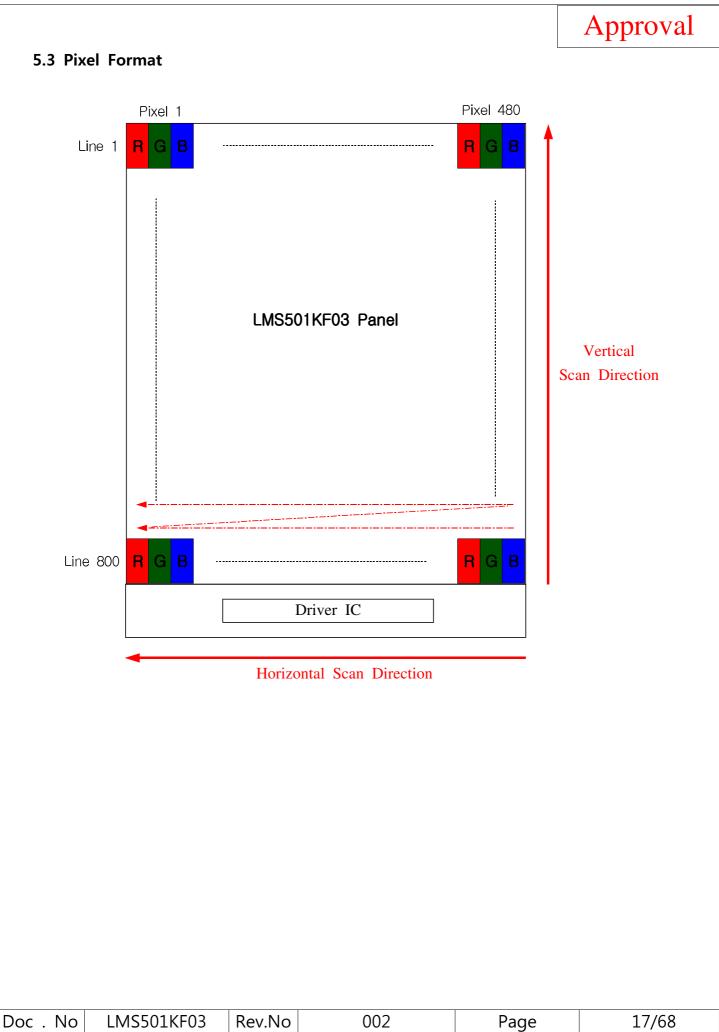
No.	Symbol	Description	No.	Symbol	Description
1	N.C	No connection	27	DG2	RGB Data (G2)
2	VDD3	Analog/Logic Power	28	DG3	RGB Data (G3)
3	VD05	(3.0V)	29	DG4	RGB Data (G4)
4	N.C	No connection	30	DG5	RGB Data (G5)
5	VDD1	I/O I/F Power (1.8V)	31	DG6	RGB Data (G6)
6	N.C	No connection	32	DG7	RGB Data (G7)
7	PCLK	Dot Clock	33	GND	Ground
8	DE	Data Enable	34	DRO	RGB Data (R0)
9	HSYNC	Horizontal Sync	35	DR1	RGB Data (R1)
10	VSYNC	Vertical Sync	36	DR2	RGB Data (R2)
11	N.C	No connection	37	DR3	RGB Data (R3)
12	SDI	SPI Data Input	38	DR4	RGB Data (R4)
13	CSX	chip selection	39	DR5	RGB Data (R5)
14	SCL	SPI Clock	40	DR6	RGB Data (R6)
15	GND	Ground	41	DR7	RGB Data (R7)
16	DBO	RGB Data (B0)	42	GND	Ground
17	DB1	RGB Data (B1)	43	RESET	RESET
18	DB2	RGB Data (B2)	44	CABC_PWM	PWM Signal Out
19	DB3	RGB Data (B3)	45	N.C	No connection
20	DB4	RGB Data (B4)	46	LED2-	LED Cathode 2
21	DB5	RGB Data (B5)	47	LED1-	LED Cathode 1
22	DB6	RGB Data (B6)	48	N.C	No connection
23	DB7	RGB Data (B7)	49	LED2+	LED Anode 2
24	GND	Ground	50	LED1+	LED Anode 1
25	DG0	RGB Data (G0)	51	GND	Ground
26	DG1	RGB Data (G1)	-	-	-

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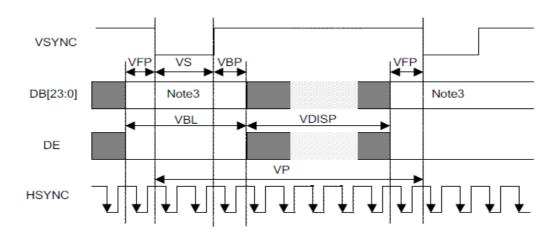
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5.2 Input Signal, Basic Display Colors and Gray Scale of Each Colors

COLOR												DA	FA S	SIG	NAL			1								GRAY
	DISPLAY				1	ED			1			1	GRI		1						BL				1	SCALE LEVEL
					R3	R4		R6	R7		G1		G3	G4			G7	B0	B1	B2	B3	B4	B5			
-	BLACK	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	-
-	BLUE	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	1	1	1	1	1	1	-
-	GREEN	0	0	0	0	0	0	0	0	1	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	-
BASIC	CYAN	0	0	0	0	0	0	0	0	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	-
COLOR	RED	1	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	-
	MAGENTA	1	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	1	1	1	1	1	1	1	1	-
-	YELLOW	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	-
	WHITE	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	-
_	BLACK	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	R0
	DARK	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	R1
GRAY		0	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	R2
SCALE	I.	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	R3~R252
OF	\downarrow	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	
RED	LIGHT	1	0	1	1	1	1	1	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	R253
		0	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	R254
	RED	1	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	R255
	BLACK	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	G0
	DARK	0	0	0	0	0	0	0	0	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	G1
GRAY		0	0	0	0	0	0	0	0	0	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	G2
SCALE	Ι	:			:	:	:	:	:	:			:	:	:	:	:	:			:	:	:	:	:	G3~G252
OF	\downarrow	:			:	:	:	:	:	:			:	:	:	:	:	:			:	:	:	:	:	
GREEN	LIGHT	0	0	0	0	0	0	0	0	1	0	1	1	1	1	1	1	0	0	0	0	0	0	0	0	G253
_		0	0	0	0	0	0	0	0	0	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	G254
	GREEN	0	0	0	0	0	0	0	0	1	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	G255
	BLACK	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	B0
	DARK	0			0	0	0	0	0	0	0	0	0	0	0	0		1	0	0	0	0	0	0	0	B1
GRAY	↑ DAIXX	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0		0	1	0	0	0	0	0	0	B2
SCALE	i.	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:	B3~B252
OF	\downarrow	:	:	:	:	:	:	:	:	:	:	:	:	:	:	:		:	:	:	:	:	:	:	:	8055
BLUE	LIGHT	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0		1	0	1	1	1	1	1	1	B253
F		0	0	0	0	0	0	0	0	0	0	0	0	0	0	0		0	1	1	1	1	1	1	1	B254
	BLUE	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	1	1	1	1	1	1	B255

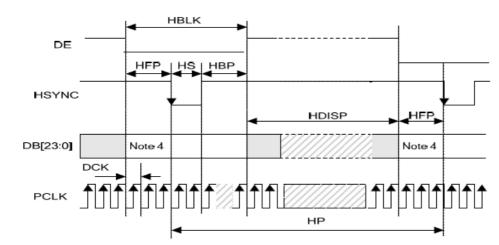


6. Interface Timing 6.1 Vertical Timing



Signal	Symbol	Min.	Тур.	Max.	Unit	Note
Frame Frequency	fFRM	-	60	-	Hz	
VSYNC(Frame) Period	VP	-	816	-	Н	
VSYNC Low width	VS	-	4	-	Н	
Vertical Display Period	VDISP	-	800	-	Н	
Vertical Back porch	VBP	-	6	-	Н	
Vertical Front porch	VFP	-	6	-	Н	

6.2 Horizontal Timing

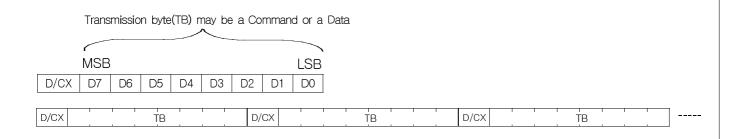


	Signal	Symbol	Min.	Тур.	Max.	Unit	Note
н	SYNC(1H) Period	HP	-	502	-	DotCLK	
н	SYNC Low width	HS	-	6	-	DotCLK	
Horiz	ontal Display Period	HDISP	-	480	-	DotCLK	
Но	izontal Back porch	HBP	-	8	-	DotCLK	
Hor	izontal Front porch	HFP	-	8	-	DotCLK	
D	OTCLK Frequence	DCK	-	24.576	-	MHz	
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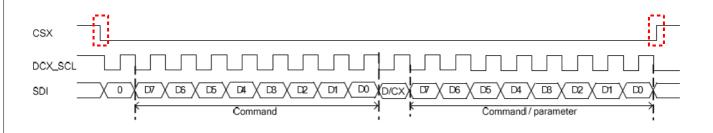
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6.3 SPI Signal

6.3.1 Serial data stream format, write mode

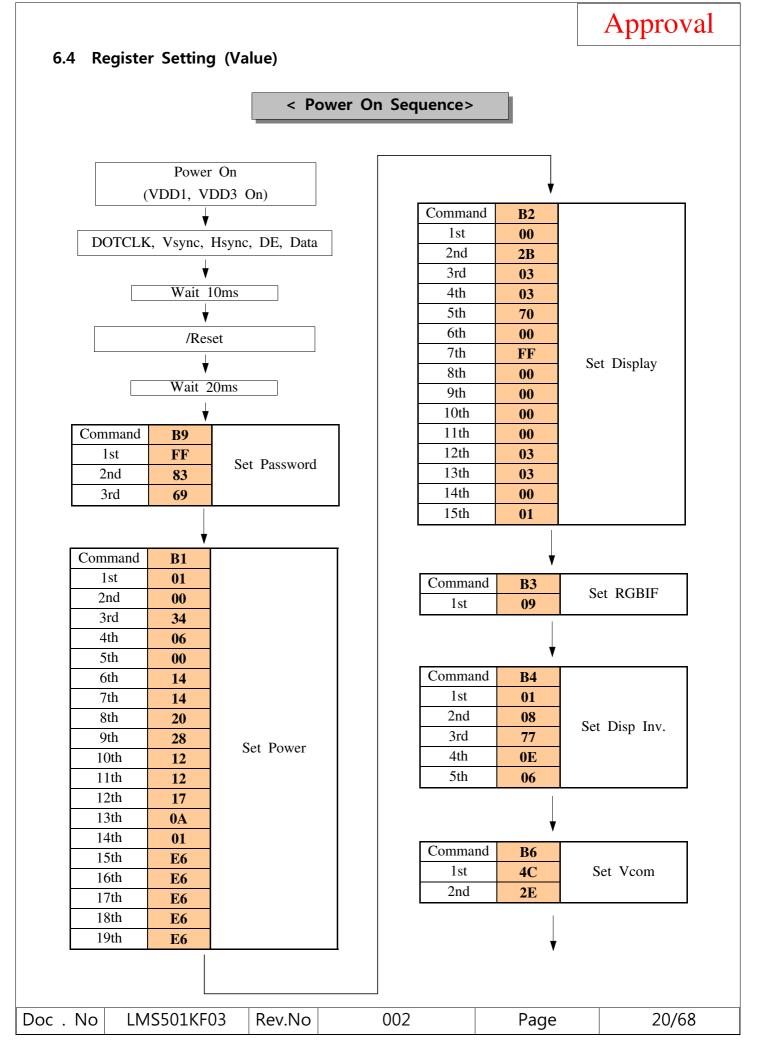


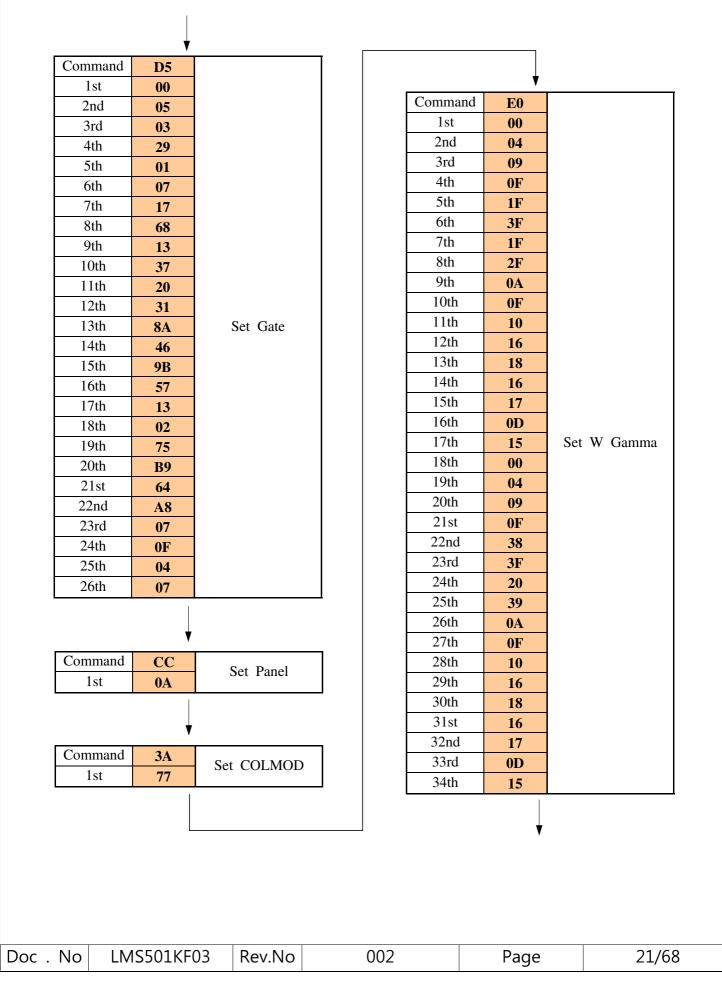
6.3.2 Serial Interface protocol



This serial data packet contains a control bit D/CX and a transmission byte. If D/CX is low, the transmission byte is command byte. If D/CX is high, transmission byte is stored in to command register or GRAM. The MSB is transmitted first. A falling edge on CSX enables the serial interface and indicates the start of data transmission.

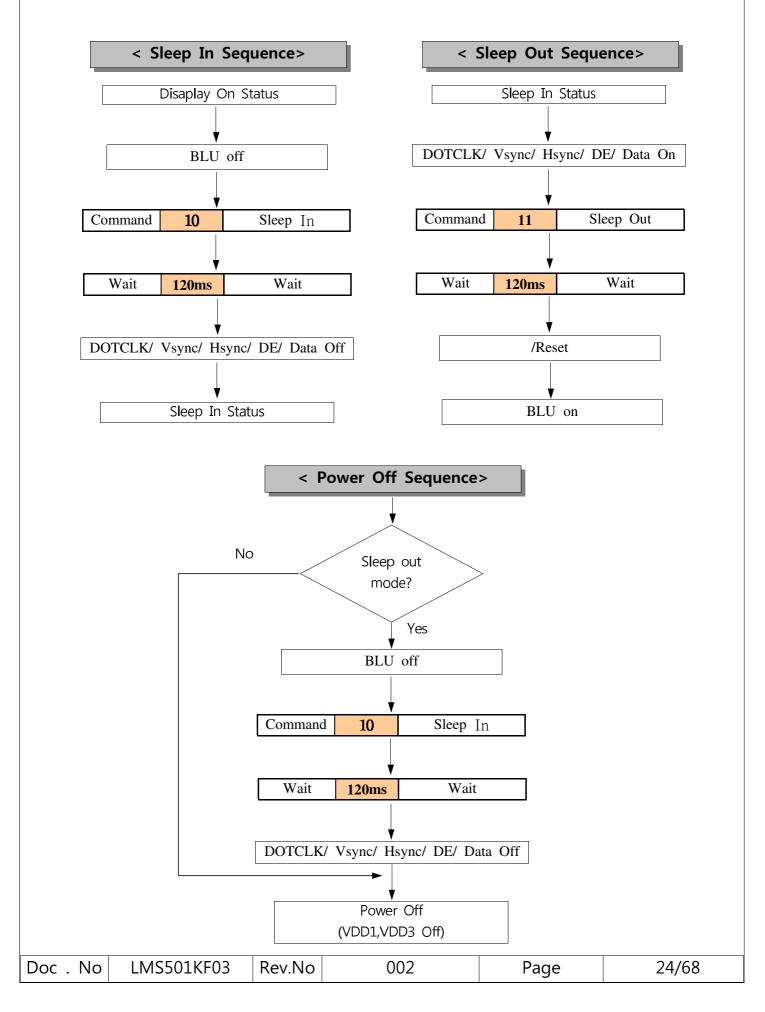
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	¥					
Command	C1					
1st	01			44th	02	
2nd	03				03	
3rd	07			45th	07 0F	
4th	0F			46th	0F	
5th	1A			47th	19	
6th	22			48th	20	
7th	2C			49th	2A	
8th	33			50th	31	
9th	3C			51st	39	
10th	46			52nd	42	
11th	4F			53rd	4B	
12th	58			54th	53	
13th	60			55th	5B	
14th	<u> </u>			56th	63	
15th	71			57th	6B	
16th	71 79			58th	73	
17th	82			59th	7B	
18th	<u>82</u> 89			60th	83	
19th	<u> </u>			61st	8 A	
20th				62nd	92	
2001 21st	<u>9A</u>			63rd	9B	
21st 22nd	A1	Set RGB Gamma		64th	A2	Sat DCD Commo
	<u>A9</u>			65th	AA	Set RGB Gamma
23rd	<u>B1</u>			66th	B2	
24th	B9			67th	BA	
25th	<u>C1</u>			68th	C2	
26th	C9			69th	СА	
27th	CF			70th	D0	
28th	D6			71st	D8	
29th	DE			72nd	E1	
30th	E5			73rd	E8	
31st	EC			74th	F0	
32nd	F3			75th	F8	
33rd	F9			76th	FF	
34th	FF			77th	F7	
35th	DD			78th	D8	
36th	39			79th	BE	
37th	07			80th	A7	
38th	1C			81st	39	
39th	CB			82nd	<u> </u>	
40th	AB			8211d 83rd		
41st	5 F			8310 84th	85 8C	
42nd	49				8C	
43rd	80			85th	C0	
			.		↓ ▼	
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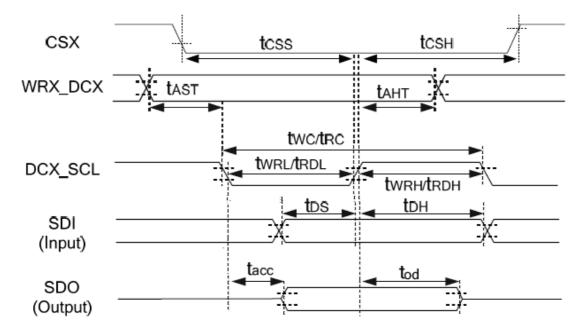
	I				Approval
964			r I	L L	
86th	04		Comman	d 36	
87th	07		1st	10 S	Set UPDN
88th	0C		150	10	
89th 90th	17				
	1C			*	
91st	23		Comman	d 11 S	Sleep Out
92nd 93rd	2B				
931d 94th	34			•	
94th 95th	3B		Wait	120	Wait
95th	43		w an	120ms	vv alt
90th	4C				
97th 98th	54 50			*	
98th	5B		Comman	d 29	Disp On
100th	63				
100ui 101st	6A			•	
101st	73 7A				
102nd	82			BLU on	
103tu 104th	8A				
104th	91				
105th	91 98				
100th	90 A1	Set RGB Gamma			
107th	AI A8				
109th					
1109th	B0 B7				
111th	C1				
111th	C1 C9				
112th	CF				
113th	D9				
115th	E3				
115th	EA				
117th	F4				
117th	FF				
119th	00				
120th	00				
120th	00				
121st 122nd	00				
122rd	00				
1251d	00				
12.1th	00				
125th	00				
127th	00				
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6.5 AC Characteristic

6.5.1 Serial Interface Timing Characteristic



(VSSA=0V, VDD1=1.8V, VDD2=2.8V, VDD3=2.8V, T_A = 25 °C)

Signal	Symbol	Parameter	Min.	Max.	Unit	Description
CSX	tcss	Chip select setup time (Write)	40	-	ns	-
	tcsH	Chip select setup time (Read)	40	-		
WRX DCX	t AST	Address setup time	10	-	200	
WHA_DOA	tант	Address hold time (Write/Read)	10	-	ns	-
DCX SCL	twc	Write cycle	100	-		
(Write)	twrn	Control pulse "H" duration	40	-	ns	-
(write)	twrl	Control pulse "L" duration	40	-		
	tec	Read cycle	150	-		
DCX_SCL	t RDH	Control pulse "H" duration	60	-	ns	-
(Read)	TRDL	Control pulse "L" duration	60	-		
SDI/SDO	tos	Data setup time	30	-		
(Input)	tот	Data hold time	30	-	ns	For maximum CL=30pF
SDI/SDO	t RACC	Read access time	10	-		For minimum CL=8pF
(Output)	top	Output disable time	10	50	ns	

Note: The input signal rise time and fall time (tr, tf) is specified at 15 ns or less. Logic high and low levels are specified as 30% and 70% of VDD1 for Input signals.

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Approval 6.5.2 Image Data Interface Timing Characteristic VSHT VSST VSYNC HSST HSHT HSYNC PCLKCYC PCLKHT PCLKLT PCLK DST DHT DB[15:0], DB[17:0], DB[23:0]. ĎΕ

(VSSA=0V, VDD1=1.8V, VDD2=2.8V, VDD3=2.8V, T_A=25°C)

Parameter	Symbol	Condition	Min.	Тур.	Max.	Unit
Vertical sync. setup time	VSST	-	5	-	-	ns
Vertical sync. hold time	VSHT	-	5	-	-	ns
Horizontal sync. setup time	HSST	-	5	-	-	ns
Horizontal sync. hold time	HSHT	-	5	-	-	ns
Pixel clock cycle	PCLKCYC	VRR ⁽⁴⁾ = 60Hz		40.69 ⁽³⁾		nc
when RGB I/F is running	FULKCIC		-	40.09	-	ns
Pixel clock low time	PCLKLT	-	5	-	-	ns
Pixel clock high time	PCLKHT	-	5	-	-	ns
Data setup time DB[23:0]	DST	-	5	-	-	ns
Data hold time DB[23:0]	DHT	-	5	-	-	ns

Note:(1) Signal rise and fall times are equal to or less than 20ns.

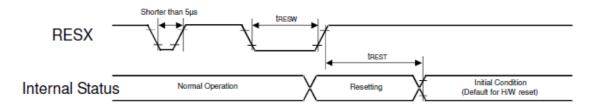
(2) Input signals are measured by 0.3xVDD1 for low state and 0.7xVDD1 for high state.

(3) 24.576MHz

(4) VRR : Vertical Refresh Rate, equal to VSYNC frequency.

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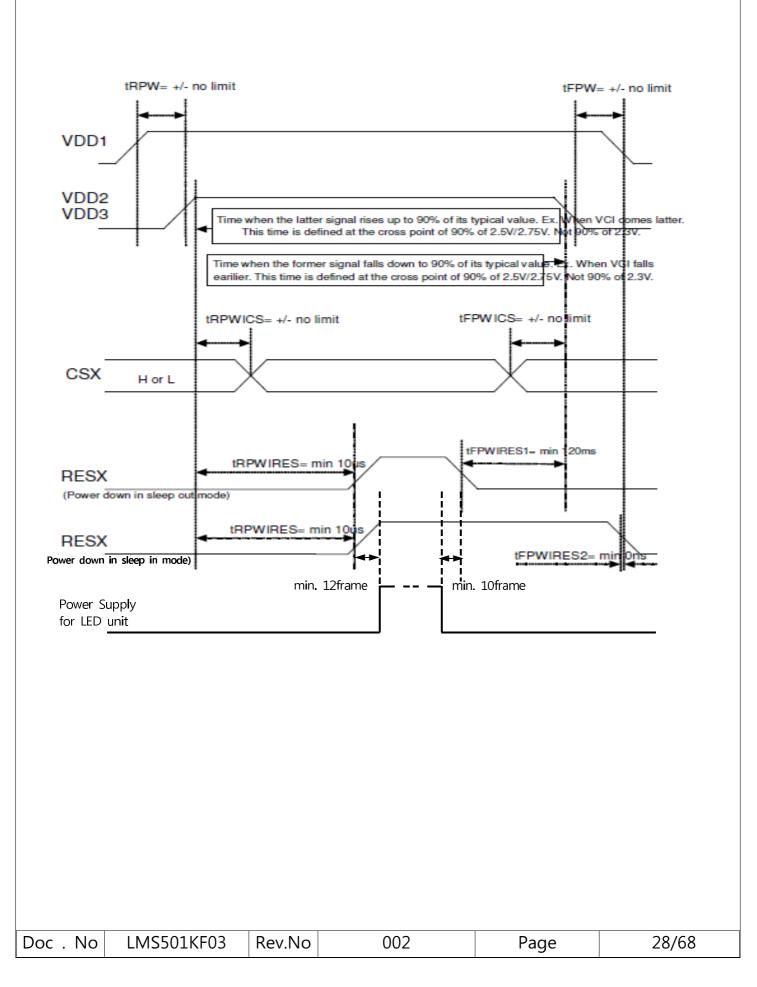
6.5.3 Reset Input Timing Characteristic



Symbol	Parameter	Related pins	Min.	Тур.	Max.	Note	Unit
t _{RESW}	Reset low pulse width ⁽¹⁾	RESX	10	-	-	-	μs
+	Pasat complete time ⁽²⁾	-	-	-	5	When reset is applied during Sleep In mode	ms
t _{rest}	Reset complete time ⁽²⁾	-	-	-	120	When reset is applied during Sleep Out mode	ms

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7. Power On/Off Sequence



8. Reliability Test Result

8.1 Condition

Item	Condition	Test Result	Note
High Temperature Operating Life test	70°C, 128HR	PASS	-
Low Temperature Operating Life test	-20°C, 128HR	PASS	-
Thermal Humidity Bias test	60°C, 93%RH, 128HR	PASS	-
High Temperature and Humidity Storage	85°C, 85%RH 128HR	PASS	
Temperature Cycle ON/OFF test	-40°C ↔ 85°C [30min], ON/OFF, 30CYC	PASS	-
High Temperature Storage test	85°C, 128HR	PASS	-
Low Temperature Storage test	-40°C, 128HR	PASS	-
Electro-Static	Contact : ± 6 kV, 10times	PASS	(1)
Discharge test	Air : ±8kV, 10times	PASS	(1)
Box Vibration Test	RANDOM 6-200hz 1.074Grms, x/y/z axis, 각1Hr (SMALL BOX)	PASS	(2)
Box Drop Test	(10kg↓_76Cm, 11kg↑_66Cm) 1edge 3corner 6sides, 10times	PASS	-
Surface pressure test	Module 4PB : More than 12.78kgf @ Weibull 10%	PASS	(3)
	Driver IC 4PB : More than 3.63kgf @ Weibull 10%	PASS	

Note (1) Main-LCD, 2 times to every 5 corners of active area

Note (2) Basic transportation by common carrier environmental, 514.4 MIL-STD-810E

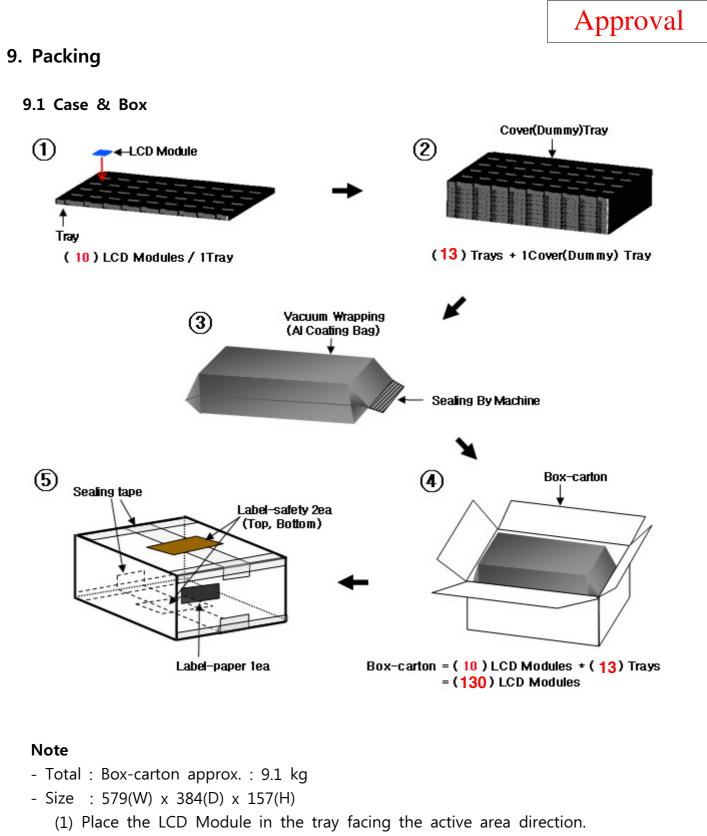
Note (3) Surface pressure test

Module 4PB	Driver IC 4PB		
평가단위: Module face up 지지 JIG간 거리 : 40mm 누름 JIG간 거리 : 20mm JIG 누름 속도 : 5mm/min JIG Center : CF center	평가단위:Module bottom up (Driver IC 배면) 지지 JIG간 거리 : 30mm 누름 속도 : 5mm/min		

8.2 Judgement

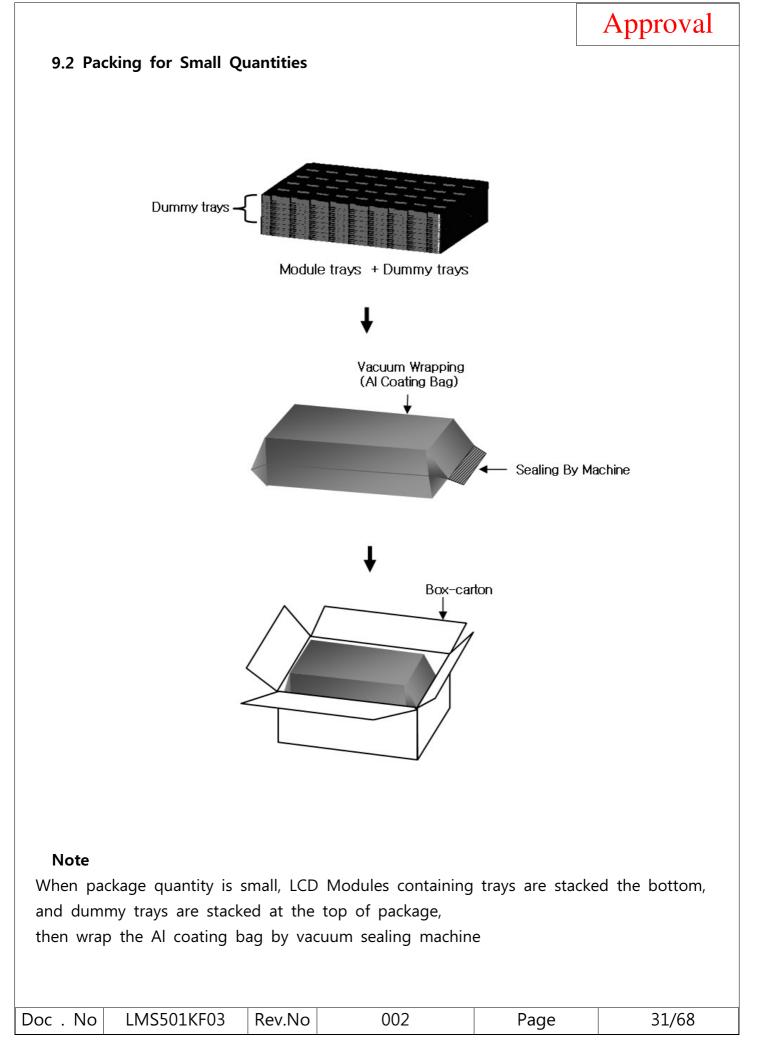
- (1) Main LCD should work under the normal condition.
- (2) After the temperature and humidity test,
 - the luminance and CR(Contrast Ratio) should not be changed over 50% compared with those before the test.

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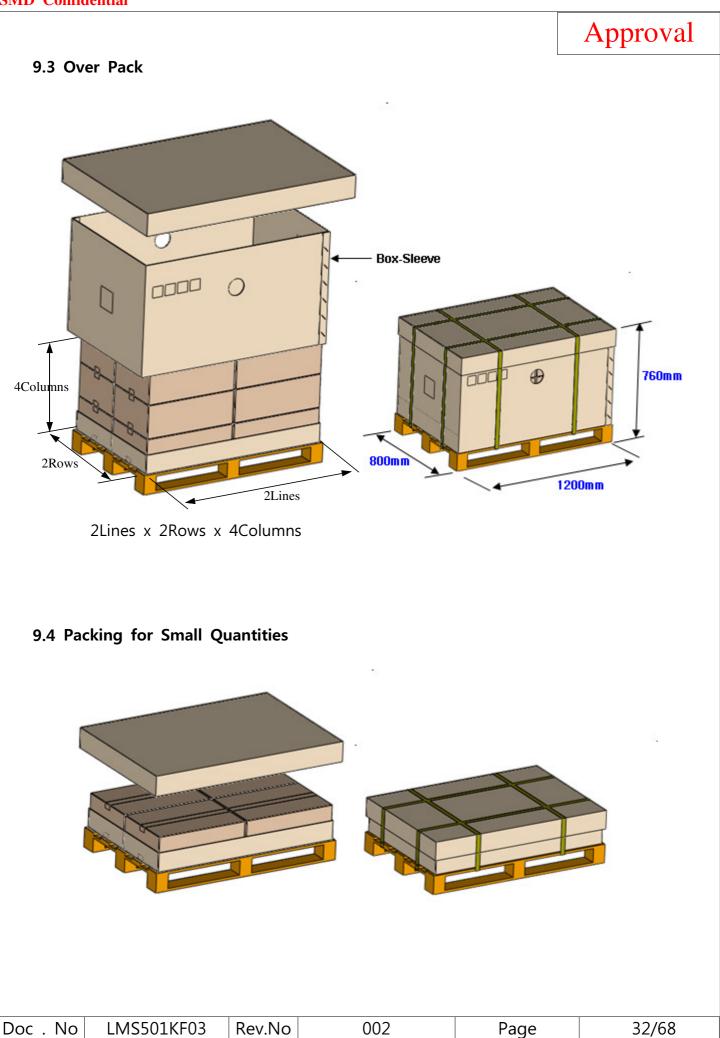


- (2) Stack the trays and cover (dummy) tray.
- (3) Resistance of tray surface : $10^6 \sim 10^9 \Omega$.
- (4) Wrap the Al coating bag by vacuum sealing machine.
- (5) Put the bag in the Box-carton.
- (6) Seal the Box-carton and affix the Label-safety & Label-paper.

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10. Marking & Others

A nameplate bearing followed by is affixed to a shipped product at the Specified location on each product.

10.1 Laser Printing on the back side of TFT-LCD Module

- 10 digits marking on the back side of TFT-LCD module

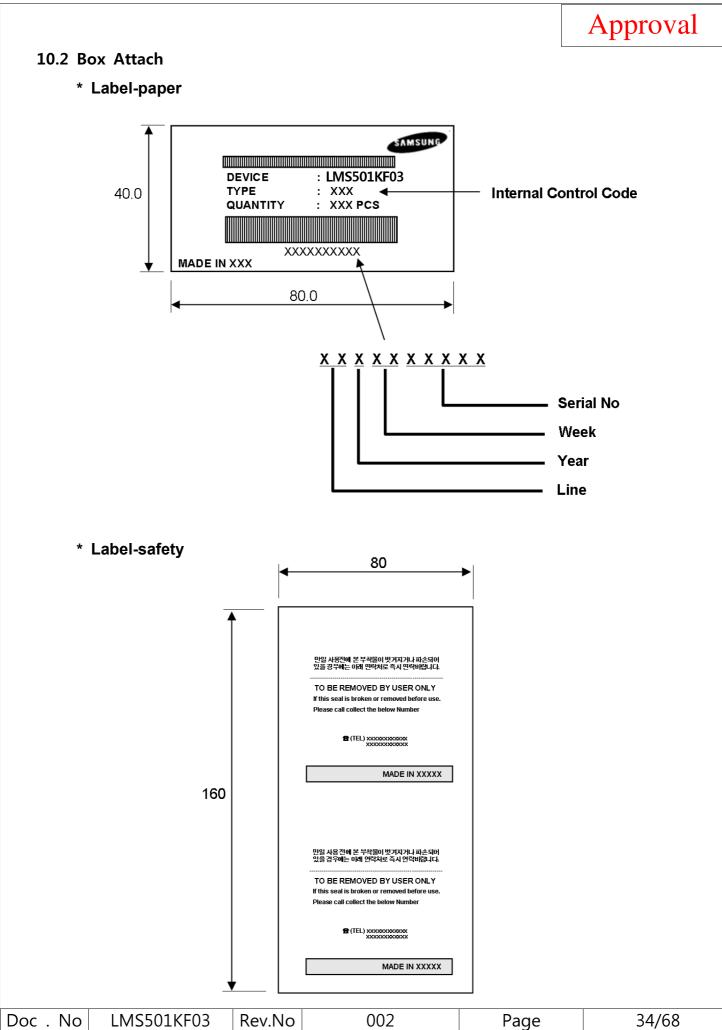
К	А	10	05	28	А	0
1	2	3	4	5	6	\bigcirc

1 Module Site

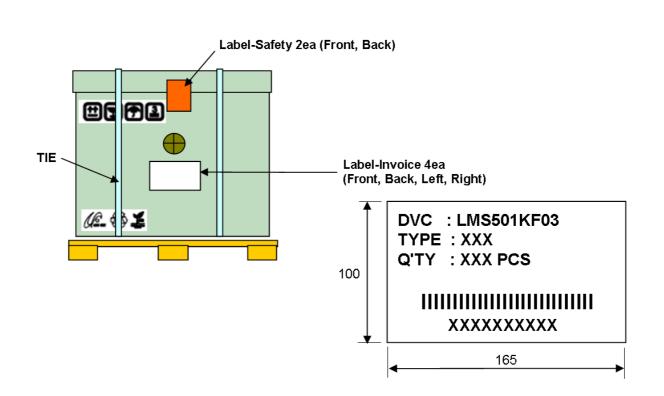
→ K (SEC), V (Voda), I (IDS Korea), Z(BK), C (DTC), T (Intelligent), H (IDS, China), L (E-Litecom), D (DSMD), J (CSMD), M (SM HITECH)

- Production Shift
- ③ Year: 10(2010), 11(2011)
- ④ Month: 01(January), 02(February), 03(March)
- (5) Day
- ⑥ ASSY 조립 LINE
- ⑦ SAMPLE 구분

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10.3 Over Pack Attach





11. General Precautions

11.1 Handling

- (a) When the module is assembled, it should be attached to the system firmly. Be careful not to twist and bend the module.
- (b) Refrain from strong mechanical shock and / or any force to the module. In addition to damage, this may cause improper operation or damage to the module and back-light unit.
- (c) Note that polarizers are very fragile and could be easily damaged. Do not press or scratch the surface harder than a HB pencil lead.
- (d) Wipe off water droplets or oil immediately. If you leave the droplets for a long time, Staining and discoloration may occur.
- (e) If the surface of the polarizer is dirty, clean it using some absorbent cotton or soft cloth.
- (f) The desirable cleaners are water, IPA(Isopropyl Alcohol) or Hexane. Do not use Ketone type materials(ex. Acetone), Ethyl alcohol, Toluene, Ethyl acid or Methyl chloride. It might permanent damage to the polarizer due to chemical reaction.
- (g) If the liquid crystal material leaks from the panel, it should be kept away from the eyes or mouth. In case of contact with hands, legs or clothes, it must be washed away thoroughly with soap.
- (h) Protect the module from static , it may cause damage to the Integrated Gate Circuit.
- (i) Use finger-stalls with soft gloves in order to keep display clean during the incoming inspection and assembly process.
- (j) Do not disassemble the module.
- (k) Protection film for polarizer on the module shall be slowly peeled off just before use so that the electrostatic charge can be minimized.
- (I) Pins of I/F connector shall not be touched directly with bare hands

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11.2 Storage

- (a) Do not leave the panel in high temperature, and high humidity for a long time. It is highly recommended to store the module with temperature from 0 to 35°C and relative humidity of less than 70%.
- (b) Do not store the TFT-LCD module in direct sunlight.
- (c) The module shall be stored in a dark place. It is prohibited to apply sunlight or fluorescent light during the store.

11.3 Operation

- (a) Do not connect, disconnect the module in the "Power On" condition.
- (b) Power supply should always be turned on/off by the "Power on/off sequence"

11.4 Others

- (a) The Liquid crystal is deteriorated by ultraviolet, do not leave it in direct sunlight and strong ultraviolet ray for many hours.
- (b) Avoid condensation of water. It may result in improper operation or disconnection of electrode.
- (c) Do not exceed the absolute maximum rating value. (the supply voltage variation, input voltage variation, variation in part contents and environmental temperature, and so on) Otherwise the panel may be damaged.
- (d) If the panel displays the same pattern continuously for a long period of time, it can be the situation when the image "Sticks" to the screen.
- (e) This panel has its circuitry FPC on the bottom side and should be handled carefully in order not to be stressed.

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12. Appendix

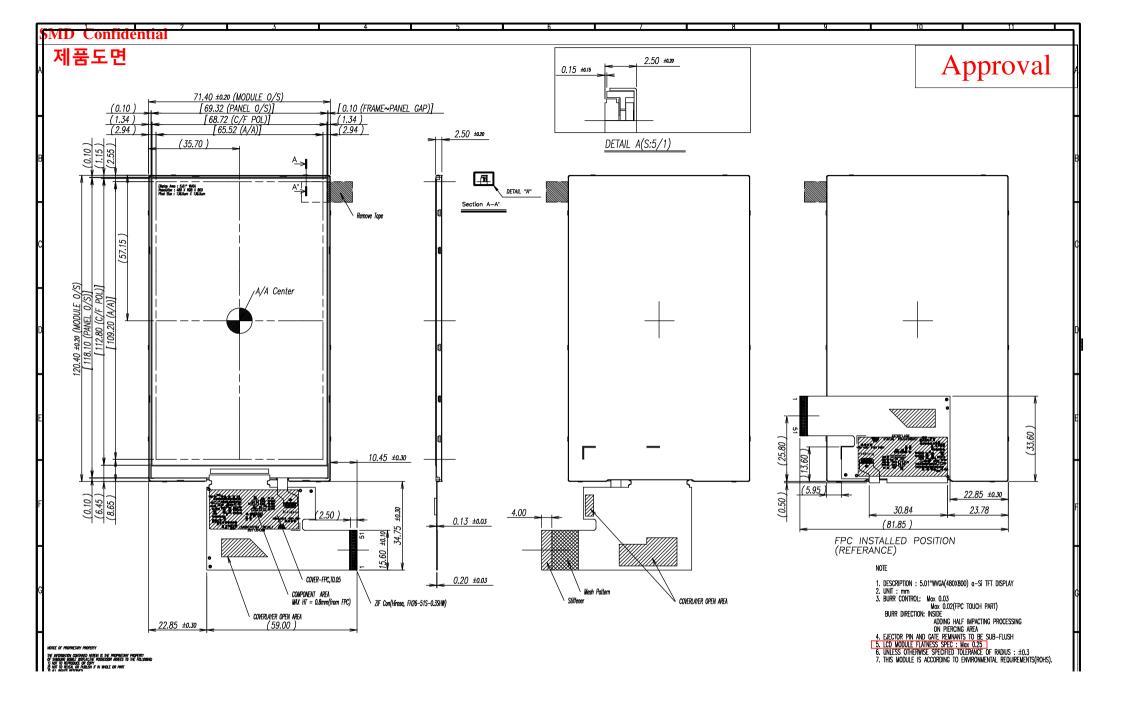
-. 제품도면 39 _____ -. 제품 Tray 도면 40 _____ -. MAIN FPC 회로도 41 _____ -. MAIN FPC PARTLIST 42 _____ -. MAIN FPC 부품배치도 43 _____ -. MAIN FPCB 도면 44 ------. MAIN FPCB Structure 45 _____ -. Material List 46 _____ -. Module QCP 47 _____ -. 환경유해물질 성적서 _____ 50

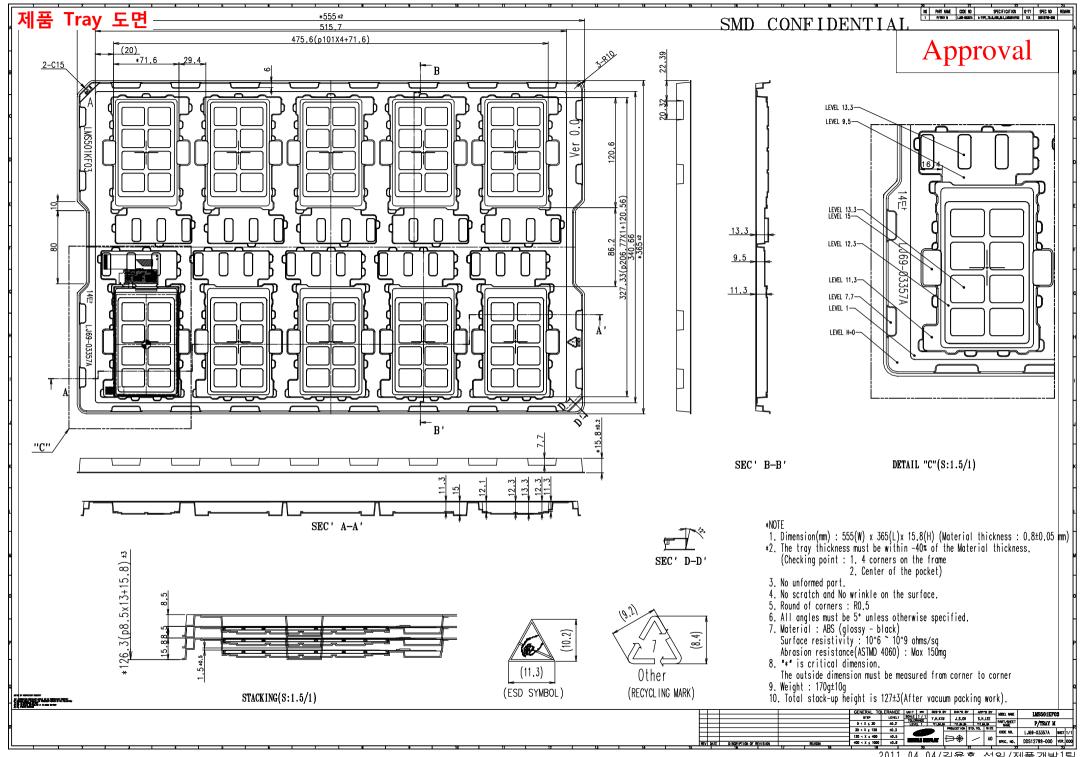
-. 검사표준

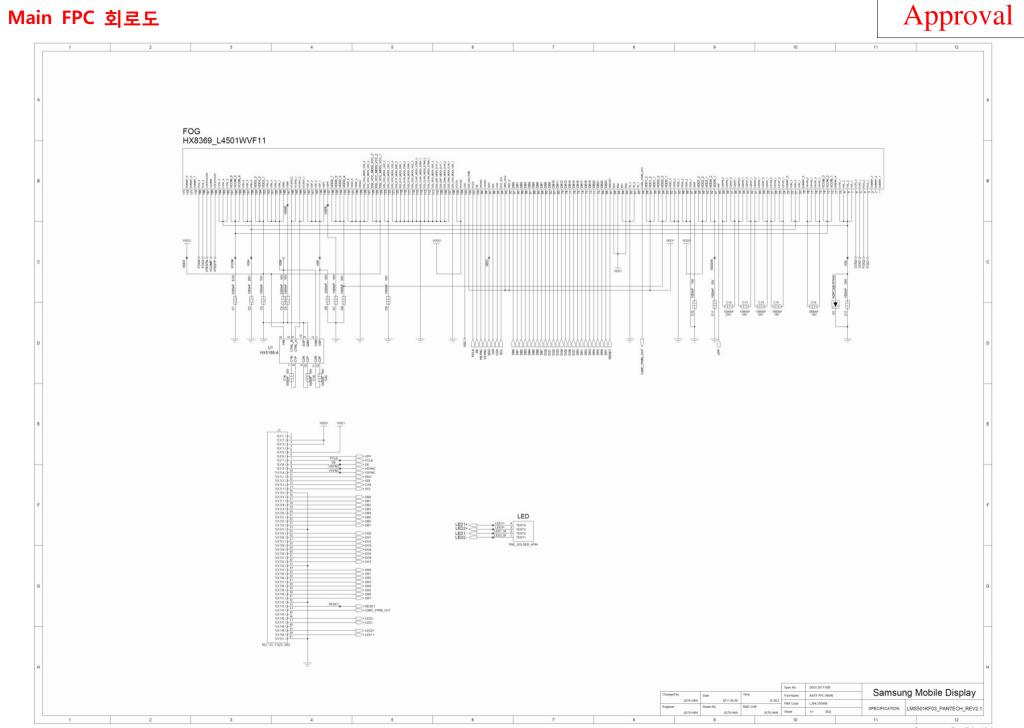
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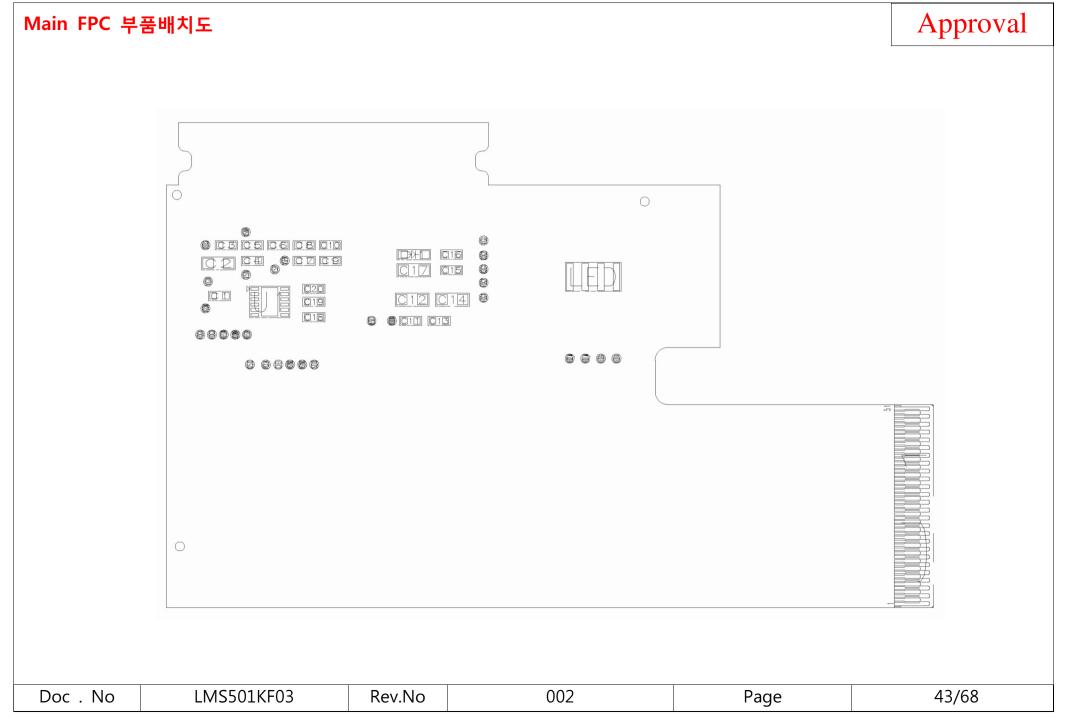
271971307414428

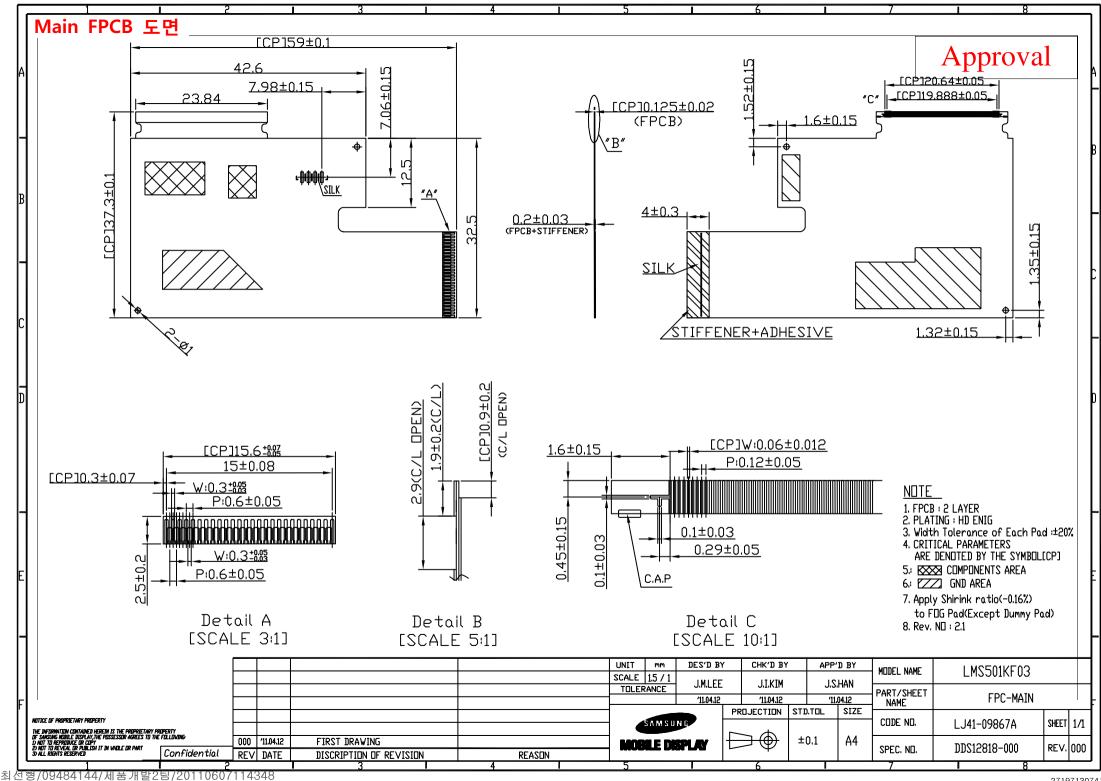
Main FPC Partlist

NO	CATEGORY	REFERENCE	Q'ty	SPECIFICATION
1	C- CER,CHIP	C3,C5,C7,C8,C9,C10 C11,C16,C18,C19,C20	11	1000nF,10%,10V,X5R,1005
2	C- CER,CHIP	C13,C15	2	1000nF,10%,16V,X5R,1005
3	C- CER,CHIP	C2,C12,C14,C17	4	1000nF,10%,25V,X5R,1608, 0.55Tmax
4	C- CER,CHIP	C1	1	2200nF,10%,6.3V,X5R,1005
5	C- CER, CHIP	C4,C6	3	2200nF,10%,10V,X5R,1005
6	DIODE- SCHOTTKY	D1	1	RB521S- 30G,30V,200mA,ESC(EMD2)
7	DC- DC IC	U1	1	HX- 5186- A

Note: Connector specification for LCD connection refers to Input Terminal Pin Assignment in page 15 and Outline Dimension in page 39

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Main FPCB Structure

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1. 본체

충수		재료	두께		업체	품명	HALOGEN FREE 적용 여부	
	C/L	film	12.5	<i>µ</i>	HANWHA	HGCS-A405L	H/F	
	072	접착제	20.0	<i>µ</i> /m			1.17.1	
		동도금	8.0	<i>µ</i> ∕m				
	FCCL	Copper	12.0	<i>µ</i> ∕m		DL-2012-E		
1,2		Base film	20.0	<i>µ</i> ∕m	LG화학		H/F	
		Copper	12.0	<i>µ</i> /m				
		동도금	8.0	<i>µ</i> ∕m				
	C/L	접착제	20.0	<i>µ</i> /m	HANWHA	HGCS-A405L	H/F	
	072	film	12.5	<i>µ</i> ∕m		HOUS MADE	1 17 1	
		전체두께	125.0	<i>µ</i> ∕m				

충수		재료		두꺼		업체	품명	HALOGEN FREE 적용 여부
	Bending부 Ink		BOTTOM		<i>µ</i> ∕m			
	Silk marking	TOP	BOTTOM	20	<i>µ</i> m	TAIYO	S-200WEF	H/F
	Black silk		BOTTOM		<i>µ</i> /m			
기타	Silver Paste		BOTTOM		<i>µ</i> ∕m			
 부착재	Over Coat		BOTTOM		<i>µ</i> /m			
	PSR	□ Yellow			<i>µ</i> /m			
	FON	□ Blue			<i>µ</i> /m			
	보강판	🗆 TOP 🗖	BOTTOM	75	<i>µ</i> /m	이녹스	MSH-3X-00FX	H/F
	기타 접착제	□ TOP ■	BOTTOM	35	<i>µ</i> /m	SONY	D3450	H/F

2. 단면도

원자재 구	·성 두께	압착부 Open 면	BENDING 영역	압착부 후면 Overlap	Body 영역	C/N 연결부	Connector
PI Film	12.5						
Adhesiv	e 20.0						
Copper Pla	ating 8.0						
Coppe	r 12.0						
Adhesiv	e						
Base Filr	m 20.0						
Adhesiv	e						
Coppe	r 12.0						
Copper Pla	ating 8.0						
Adhesiv	e 20.0						
PI Film	12.5						
Adhesiv	e 35.0						
Stiffene	er 75.0						
Total Thick	ness	72.5	72.5	72.5	125.0	125.0	202.5
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Material List

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CATEGORY	Maker	Material	Specification			
Panel	SMD	Glass	5.01", 69.32(W)*118.1(H)*0.8(T)			
		Liquid Crystal				
Polarizer-CF	KORENO	NZD-VEGQ1763CUHC	MS501KF03, NZDCVEQUHC-KS17, 68.72(H)x112.8(V), H/C			
Polarizer-TFT	KORENO	APCFH2ZDVEQSU22	LMS501KF03, APCFH2ZDVEQSU22, 68.72(H)x112.8(V), APC			
		Glass 5.01", 69.32(W)*118.1(ENO NZD-VEGQ1763CUHC MS501KF03, NZDCVEQUHC-KS17, ENO APCFH2ZDVEQSU22 LMS501KF03, APCFH2ZDVEQSU22, Aluminum Gold HX8369-A,COG,312,1448,30un C Gold HX8369-A,COG,312,1448,30un joo Bow 538S LMS501KF03, T0.05, W35.1, joo Bow 538S LMS501KF03, T0.05, W35.1, Silk (S-200WEF) CoverLay (HGCS-A405L) LMS501KF03, 37.3X59.0, 511 LEX FCCL (DL-2012-E) LMS501KF03, 37.3X59.0, 511 CoverLay (HGCS-A405L) Adhesive (D3450) Stiffener (MSH-3X-00FX) FRAME-MOLD (PC) LGP (PC) CHASSIS-BOTTOM (SUS201) ASSY FPC-LED (PI) Stiffer (DE-2012-E) Stiffer (DA-2012-E)				
IC Driver Source	$ \begin{array}{ c c c c c } & & & & & & & & & & & & & & & & & & &$	HX8369-A,COG,312,1448,30um,22430x1701x250				
		Silicon				
Cover FPC	Samjoo	Bow 538S	MS501KF03, NZDCVEQUHC-KS17, 68.72(H)x112.8(V), LMS501KF03, APCFH2ZDVEQSU22, 68.72(H)x112.8(V), HX8369-A,COG,312,1448,30um,22430x1701x250 LMS501KF03, T0.05, W35.1, L15.4, GREEN LMS501KF03, 37.3X59.0, 51P/173P ,2L ,V2.1 LMS501KF03, 37.3X59.0, 51P/173P ,2L ,V2.1			
		Silk (S-200WEF)				
		CoverLay (HGCS-A405L)				
Flexible Printed Circuit	t SI-FLEX	FCCL (DL-2012-E)	LMS501KF03 37 3X 59 0 51P/173P 2L V2 1			
I RADIC I I IIIICU CIICUIT		CoverLay (HGCS-A405L)				
		Adhesive (D3450)	Glass5.01", 69.32(W)*118.1(H)*0.8(T)Liquid CrystalMS501KF03, NZDCVEQUHC-KS17, 68.72(H)x112.8(V),APCFH2ZDVEQSU22LMS501KF03, APCFH2ZDVEQSU22, 68.72(H)x112.8(V),AluminumHX8369-A,COG,312,1448,30um,22430x1701x250GoldHX8369-A,COG,312,1448,30um,22430x1701x250SiliconSiliconBow 538SLMS501KF03, T0.05, W35.1, L15.4, GREENSilk (S-200WEF)CoverLay (HGCS-A405L)FCCL (DL-2012-E)LMS501KF03, 37.3X59.0, 51P/173P ,2L ,V2.1CoverLay (HGCS-A405L)LMS501KF03, 37.3X59.0, 51P/173P ,2L ,V2.1Adhesive (D3450)Stiffener (MSH-3X-00FX)FRAME-MOLD (PC)LGP (PC)CHASSIS-BOTTOM (SUS201)ASSY FPC-LED (PI)HEET-PRISM(U) (HLAS4.30B)LMS501KF03, SWDA07, S18H/S19H, 12LED, 4PINSHEET-DIFFUSER (CH19NH)SHEET-REFLECTOR (ESR)			
		Stiffener (MSH-3X-00FX)				
	Adhesive (D3450) Stiffener (MSH-3X-00FX) FRAME-MOLD (PC)					
		LGP (PC)				
		CHASSIS-BOTTOM (SUS201)				
		ASSY FPC-LED (PI)				
Back Light Unit	E-Litecom	SHEET- PROTECTOR (JS562HK)	LMS501KF03, SWDA07, S18H/S19H, 12LED, 4PIN			
Durin Englis Chin		SHEET-PRISM(U) (HLAS4.30B)				
Image: Constraint of the systemLiquid CrystalPolarizer-CFKORENONZD-VEGQI763CUHCMS501KF03, NZDCVEQUH4Polarizer-TFTKORENOAPCFH2ZDVEQSU22LMS501KF03, APCFH2ZDVEIC Driver SourceSECGoldHX8369-A,COG,312,1-IC Driver SourceSECGoldHX8369-A,COG,312,1-Cover FPCSamjooBow 538SLMS501KF03, T0.05Cover FPCSamjooBow 538SLMS501KF03, T0.05Flexible Printed CircuitSI-FLEXCoverLay (HGCS-A405L)LMS501KF03, 37.3X3Flexible Printed CircuitSI-FLEXFCCL (DL-2012-E)LMS501KF03, 37.3X3Stiffener (MSH-3X-00FX)Stiffener (MSH-3X-00FX)LMS501KF03, 37.3X3Back Light UnitE-LitecomFRAME-MOLD (PC)LGP (PC)SHEET-PRISM(U) (HLAS4.30B)SHEET-PRISM(U) (HLAS4.30B)LMS501KF03, SWDA07, SHEET-DIFFUSER (CH19NH)SHEET-PRISM(U) (HLAS4.30B)SHEET-PRISM(U) (HLAS4.30B)LMS501KF03, SWDA07, SHEET-DIFFUSER (CH19NH)						
		SHEET-REFLECTOR (ESR)				
		SHEET-PANEL (3808BH)				

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Module QCP

				LMS	S501KF0	3 Q C	공 정	성 도					
공정 FLOW		긍정명	JIG/도 구	작 업	내 용	투입 자 재	공정 불 량	관리 항목	관리 방법	관리 도구	관리 표준	조치 계획	조치 책임자
) F	PANEL 세정 CTQ	세정기	세정기 혹은 Maur 전 세정을 실시한다	nal로 POL 투입	PANEL HEO5 MLO, IPA,DI	8 이물	PAD부식 /침식 표면 얼룩	검사기기 육안 검사	농도측정기 온도계 압력계 유량계 전기전도- 측정기	CELL 세정 표준	게곡 조정	공정 관리자
) POI	L 부착		LCD 전.후면에 PC 맞추어 POL을 부荐		POL IPA	오염 버블 S/C Align	설비성 불 량 Align	육안 검사	버니어 켈리 퍼스 루뻬 Scale자	POL 부착 표준	조정	공정 관리자
	> v/	/ㅣ 2차	검사기	POL 부착 후 V/I 실시한다.	2차 화질검사를	-	특성불량	검사정밀도	육안검사	V/I Pin Board	검사표준 V/I작업 표준	조정	공정 관리자
C		L/T CTQ	Ⅰ/Ⅰ석H	Laser를 이용하여 Bar를 Cutting한[-	-	cutting 안됨 cutting 덜됨	L/T 위치 -정확성 Laser Power	육안검사	설비 indicator	L/T 표준	조정	공정 관리자
		0/G	Scale자	V/I 2차 양품에 현 를 실시한다	한해 외관 검사	_	외관불량	검사정밀도	육안검사	-	검사표준	조정	공정 관리자
Doc	. No		LMS5	501KF03	Rev.No		002		Pag	e		47/68	

			LMS501KF03	QC	공 정	! 도					
공정 FLOW	공정명	JIG/도구	작 업 내 용	투입자재	공정불량	관리 항목	관리 방법	관리 도구	관리 표준	조치 계획	조치 책임자
\bigcirc	투입전 PAD 세정	-	무진천에 IPA를 묻혀서 COG PAD부를 세정한다	무진천 IPA	COG본딩부 이물	이물 오염	육안 검사	_	COG 작업표준	정	공정 관리자
\bigcirc	COG 본딩 CTQ	ACF부착 M/C COG본딩 M/C	COG PAD면에 ACF 부착 및 D-IC 본딩을 실시하여 IC Bump와 PAD부 ITO간 전기적으로 도통 시킨다.	ACF D-IC 테프론시 트	특성불량	Align 압흔 정도 압흔 수량 IC깨짐,S/C	육안 검사	현미경 감압지 압력계 온도계	COG 작업 표준	조정	공정 관리자
\bigcirc	FPC 본딩 CTQ	ACF부착 M/C FOG압착 M/C	FOG PAD에 ACF를 부착한다. ACF가 부착된 LCD PAD면위에 FPCB를 정확하게 위치 맞춤한 후 열과 압력을 가해 ACF를 열경화 시킴으로서 LSI입 력단과 FPCB를 전기적으로 도통시킨다	실리콘 시트	특성불량	Align 압흔 정도 압흔 거리 도전볼뭉침	관리 도구 측정치	압력계 TI M ER 온도계 육안 감압지	FOG 작업 표준	조정 수리	공정 관리자
	방습제 도포 CTQ	방습제 도포기	제품의 특성상 방습이 필요로 할때 방 습제(실리콘, TUFFY)를 PAD 전면 및 후면에 도포한다. * 상 POL 보다 낮게 도포, * D-IC 올라타지 않을 것. (미세 올라탐기준:WO.3, L5.0, TO.01) * 균일 높이로 전면에 도포 될것 * 배선 및 TP 노출 없을것 * Max Glass Edge를 넘지 않을 것	방습제	외관불량	건조시간 도포범위 도포높이	육안 검사	육안	SI작업표준 제조사양서	수리	공정 관리자
	MTP	걸사기	Flicker MTP를 실시한다.	_	MTP불량	PIN 접촉	특성검사	_	검사사양서	조정 수리	공정 관리자
Doc . N	lo	LMS	501KF03 Rev.No		002		Рас	le		48/68	

		LMS501KF03 Q C 공 정 도										
공정 FLOW	공정명	JIG/도구	작 업	내용	투입 자재	공정 불량	관리 항목	관리 방법	관리 도구	관리 표준	조치 계획	조치 책임자
\bigcirc	B/L+LCD 조립	-	LCD를 PAD쪽부터 B, 립하고 Panel 테두리 가압해 준다.		B/L	외관불량	이물 & 오염 L/G 들뜸	육안 검사	육안	제조사양서	수리	공정 관리자
	LED 단자 납땜 CTQ	SOLDERING JIG	LED 단자 & FPOB단: 으로 신호를 연결히 단자를 납땜한다.		Solder Wire	특성불량	ALIGN MISS 솔더링 높이 인두기온도	검사 측정치	육안, 두께측정기	SOLDERING 작업 표준 제조사양서	조정 수리	공정 관리자
\bigcirc	REMOVE TAPE 부츠		LCD 전면 보호막 틸 TAPE를 부착한다.		REMOVE TAPE	외관불량	ALIGN MISS Tape 떨어짐	육안 검사	육안	제조사양서	수리	공정 관리자
\bigcirc	FPC 절연 Tape 부츠	-	FPC 부품 위에 절연 다	1 Tape를 부착한	절연 tape	외관불량	ALIGN MISS Tape 미부착	육안 검사	육안	제조사양서	수리	공정 관리자
	INK-JET PRINT	INKJET PRINTER	B/L후면 정해진 위; 을 실시한다. (조립 방)	9	잉크	외관불량	ALIGN MISS 마킹 안됨	육안 검사	육안	Lot- Marking 표준 제조사양서	수리 조정	공정 관리자
	F/T	검사기 검사JIG	조립 완료된 MOD'온 육안 화질 검사를 4		_	특성불량	검사정밀도	육안검사	육안 Scale자 루베	출하표준 검사사양서	수리	공정 관리자
	P/K	-	조립 완료된 MOD'왼 육안 외관 검사를 4		_	특성불량	검사정밀도	육안 검사	육안 Scale자 루뻬	출하표준 검사사양서	조정 수리	공정 관리자
	포장	-	최종검사에서 양품(포장 자재를 사용ㅎ		LABEL BOX류 쉴딩백 파레트 봉인지 쿠션시트	LABEL 미부착 수량차이	LABEL 위치 포장수량 포장방법	육안 검사	포장도면	제품표준 포장표준	조정	공정 관리자
Doc . N	No	LMS	501KF03	Rev.No		002		Pag	ge		49/68	}



Intertek

TEST SUMMARY

Applicant : Samsung Mobile Display Co., Ltd.

Address : #508, Seongseong-dong, Seobuk-gu, Cheonan-city, Chungcheongnam-do, 330-300 Korea

> Page: 1 of 2 Date: Mar. 17, 2011

Approval

 Sample Description
 : The following submitted sample(s) said to be:

 Name/Type of Model
 : LMS501KF03

 Manufacturer/Vender
 : Samsung Mobile Display Co., Ltd.

Test Method(s) : Please see the following page(s).

Test Result(s) : Please see the following page(s).

* Note 1 : This test summary shall not be reproduced except in full without the written approval of the testing laboratory.

* Note 2 : The part list is assigned by client and indicated according to their requirement and guarantee letter.

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Authorized by, Bo Park / Lab. General Manager

Intertek Testing Services Korea Ltd.Doc . NoLMS501KF03Rev.No002Page50/68



PART LIST

Page: 2 of 2 Date: Mar. 17, 2011

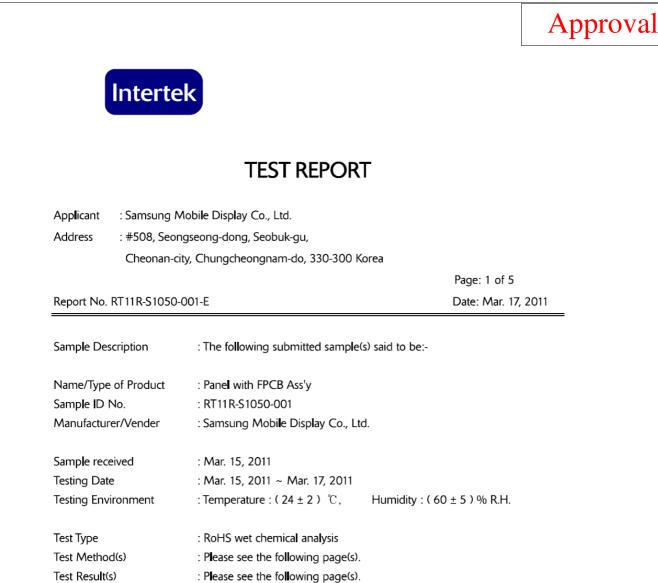
No.	Name/Type of Product	Report No.
1	Panel with FPCB Ass'y	RT11R-S1050-001-E
2	BLU	RT11R-S1050-002-E
3	Bezel	RT11R-S1050-003-E

* View of sample as received;-



***** End of Report *****

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* Note 1 : The test results presented in this report relate only to the object tested.

* Note 2 : This report shall not be reproduced except in full without the written approval of the testing laboratory.

Approved by,

2624

Jade Jang / Lab. Technical Manager

Authorized by,

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Bo Park / Lab. General Manager

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Report No. RT11R-S1050-001-E

Page: 2 of 5 Date: Mar. 17, 2011

Sample ID No. : RT11R-S1050-001 Sample Description : Panel with FPCB Ass'y

Test Item	Unit	Test Method	MDL	Result
Cadmium (Cd)	mg/kg	With reference to	0.5	N.D.
Lead (Pb)	mg/kg	IEC 62321 Edition 1.0 : 2008, by acid digestion and	5	N.D.
Mercury (Hg)	mg/kg	determined by ICP-OES	2	N.D.
Hexavalent Chromium (Cr ⁶⁺) (For non-metal)	mg/kg	With reference to IEC 62321 Edition 1.0 : 2008, by alkaline digestion and determined by UV-VIS Spectrophotometer	1	N.D.
Polybrominated Biphenyl (PBBs)				
Monobromobipheny	mg/kg		5	N.D.
Dibromobiphenyl	mg/kg		5	N.D.
Tribromobiphenyl	mg/kg	With reference to IEC 62321 Edition 1.0 : 2008,	5	N.D.
Tetrabromobiphenyl	mg/kg		5	N.D.
Pentabromobiphenyl	mg/kg		5	N.D.
Hexabromobiphenyl	mg/kg	by solvent extraction and	5	N.D.
Heptabromobiphenyl	mg/kg	determined by GC/MS	5	N.D.
Octabromobiphenyl	mg/kg		5	N.D.
Nonabromobiphenyl	mg/kg		5	N.D.
Decabromobiphenyl	mg/kg		5	N.D.
Polybrominated Diphenyl Ether (P	BDEs)	J		<u> </u>
Monobromodiphenyl ether	mg/kg		5	N.D.
Dibromodiphenyl ether	mg/kg		5	N.D.
Tribromodiphenyl ether	mg/kg		5	N.D.
Tetrabromodiphenyl ether	mg/kg	With reference to	5	N.D.
Pentabromodiphenyl ether	mg/kg	IEC 62321 Edition 1.0 : 2008,	5	N.D.
Hexabromodiphenyl ether	mg/kg	by solvent extraction and	5	N.D.
Heptabromodiphenyl ether	mg/kg	determined by GC/MS	5	N.D.
Octabromodiphenyl ether	mg/kg		5	N.D.
Nonabromodiphenyl ether	mg/kg		5	N.D.
Decabromodiphenyl ether	mg/kg		5	N.D.

Tested by : Nikkie Lee, Leo Kim, Ellen Jung, Jessica Kang

Notes : mg/kg = ppm = parts per million < = Less than N.D. = Not detected (<MDL) MDL = Method detection limit

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Report No. RT11R-S1050-001-E

Page: 3 of 5 Date: Mar. 17, 2011

Sample ID No. : RT11R-S1050-001 Sample Description : Panel with FPCB Ass'y

Test Item	Unit	Test Method	MDL	Result
Bromine (Br)	mg/kg	With reference to EN 14582, by oxygen combustion with bomb and determined by IC	30	N.D.
Chlorine (Cl)	mg/kg	With reference to EN 14582, by oxygen combustion with bomb and determined by IC	30	70

Tested by : Nikkie Lee

Notes : mg/kg = ppm = parts per million < = Less than N.D. = Not detected (<MDL) MDL = Method detection limit

* View of sample as received;-

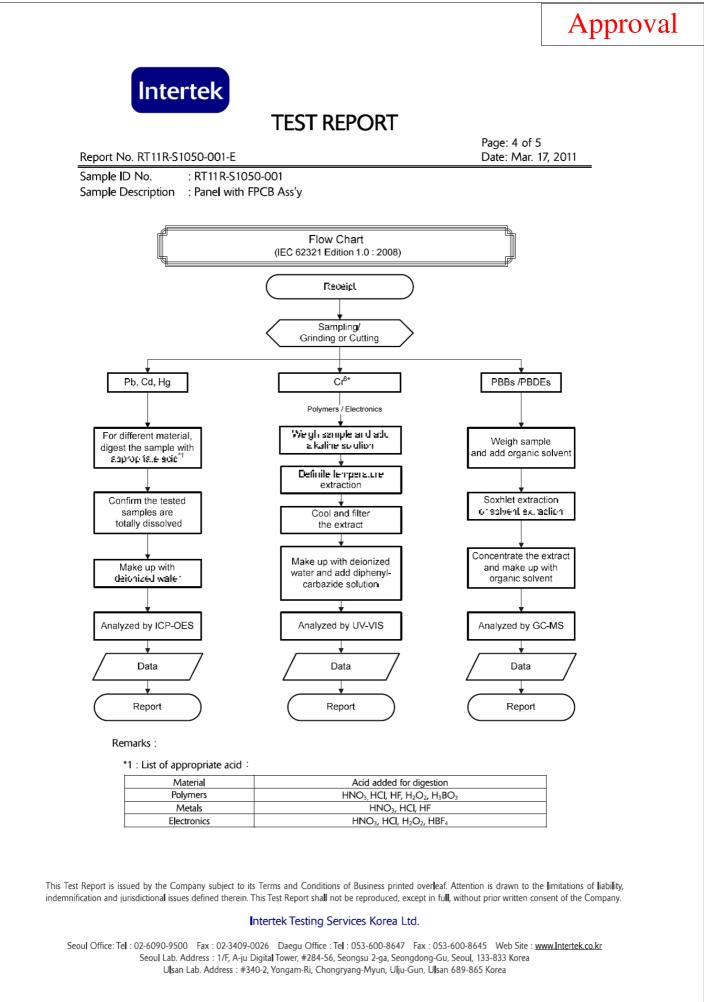


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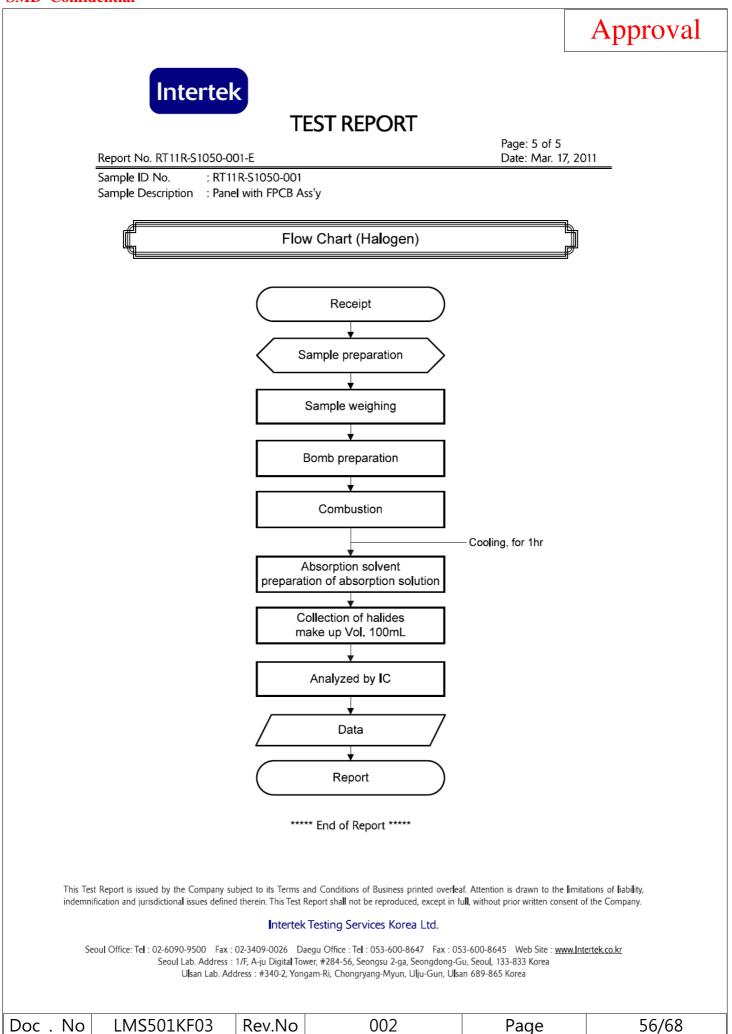
LMS501KF03

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Page







App l icant	: Samsung Mobile Display Co., Ltd.							
Address	: #508, Seong	#508, Seongseong-dong, Seobuk-gu,						
	Cheonan-city	Cheonan-city, Chungcheongnam-do, 330-300 Korea						
			Page: 1 of 5					
Report No.	Date: Mar. 17, 2011							
Sample Description		: The following submitted sample(s) said to be:-						
Name/Type of Product		: BLU						

1		
Sample ID No.	: RT11R-S1050-002	
Manufacturer/Vender	: Samsung Mobi l e Display Co., Ltd	l.
Sample received	: Mar. 15, 2011	
Testing Date	: Mar. 15, 2011 ~ Mar. 17, 2011	
Testing Environment	: Temperature : (24 \pm 2) ${}^\circ\!{}^\circ\!{}^\circ$,	Humidity : (60 ± 5) % R.H.
Test Type	: RoHS wet chemical analysis	
Test Method(s)	: Please see the following page(s).	
Test Result(s)	: Please see the following page(s).	

* Note 1 : The test results presented in this report relate only to the object tested.

* Note 2 : This report shall not be reproduced except in full without the written approval of the testing laboratory.

Approved by,

2624

Jade Jang / Lab. Technical Manager

Authorized by,

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Bo Park / Lab. General Manager

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Page: 2 of 5 Date: Mar. 17, 2011

 Report No. RT11R-S1050-002-E

 Sample ID No.
 : RT11R-S1050-002

Sample Description : BLU

Test Item	Unit	Test Method	MDL	Result
Cadmium (Cd)	mg/kg	With reference to	0.5	N.D.
Lead (Pb)	mg/kg	IEC 62321 Edition 1.0 : 2008, by acid digestion and	5	N.D.
Mercury (Hg)	mg/kg	determined by ICP-OES	2	N.D.
Hexavalent Chromium (Cr ⁶⁺) (For non-metal)	mg/kg	With reference to IEC 62321 Edition 1.0 : 2008, by alkaline digestion and determined by UV-VIS Spectrophotometer	1	N.D.
Polybrominated Biphenyl (PBBs)				
Monobromobipheny	mg/kg		5	N.D.
Dibromobiphenyl	mg/kg		5	N.D.
Tribromobiphenyl	mg/kg		5	N.D.
Tetrabromobiphenyl	mg/kg	With reference to	5	N.D.
Pentabromobiphenyl	mg/kg	IEC 62321 Edition 1.0 : 2008,	5	N.D.
Hexabromobiphenyl	mg/kg	by solvent extraction and	5	N.D.
Heptabromobiphenyl	mg/kg	determined by GC/MS	5	N.D.
Octabromobiphenyl	mg/kg		5	N.D.
Nonabromobiphenyl	mg/kg		5	N.D.
Decabromobiphenyl	mg/kg		5	N.D.
Polybrominated Diphenyl Ether (P	BDEs)			
Monobromodiphenyl ether	mg/kg		5	N.D.
Dibromodiphenyl ether	mg/kg		5	N.D.
Tribromodiphenyl ether	mg/kg		5	N.D.
Tetrabromodiphenyl ether	mg/kg	With reference to	5	N.D.
Pentabromodiphenyl ether	mg/kg	EC 62321 Edition 1.0 : 2008,	5	N.D.
Hexabromodiphenyl ether	mg/kg	by solvent extraction and determined by GC/MS	5	N.D.
Heptabromodiphenyl ether	mg/kg		5	N.D.
Octabromodiphenyl ether	mg/kg		5	N.D.
Nonabromodiphenyl ether	mg/kg		5	N.D.
Decabromodiphenyl ether	mg/kg		5	N.D.

Tested by : Nikkie Lee, Leo Kim, Ellen Jung, Jessica Kang

Notes : mg/kg = ppm = parts per million < = Less than N.D. = Not detected (<MDL) MDL = Method detection limit

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Report No. RT11R-S1050-002-E

Page: 3 of 5 Date: Mar. 17, 2011

Sample ID No.: RT11R-S1050-002Sample Description: BLU

Test Item	Unit	Test Method	MDL	Result
Bromine (Br)	mg/kg	With reference to EN 14582, by oxygen combustion with bomb and determined by IC	30	N.D.
Chlorine (Cl)	mg/kg	With reference to EN 14582,		N.D.

Tested by : Nikkie Lee

Notes : mg/kg = ppm = parts per million < = Less than N.D. = Not detected (<MDL) MDL = Method detection limit

* View of sample as received;-

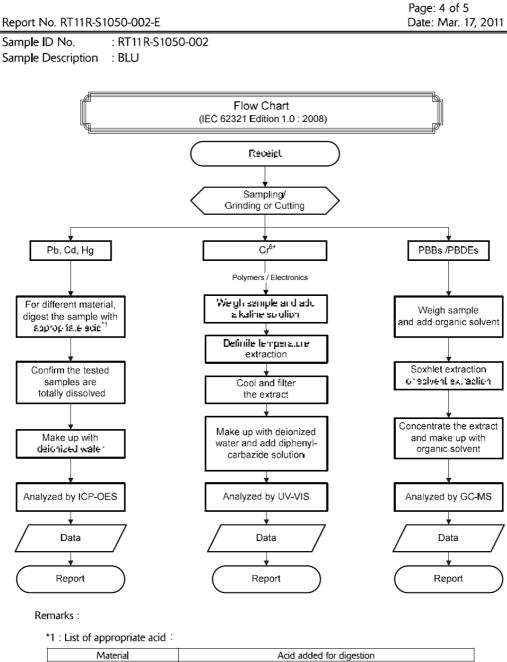


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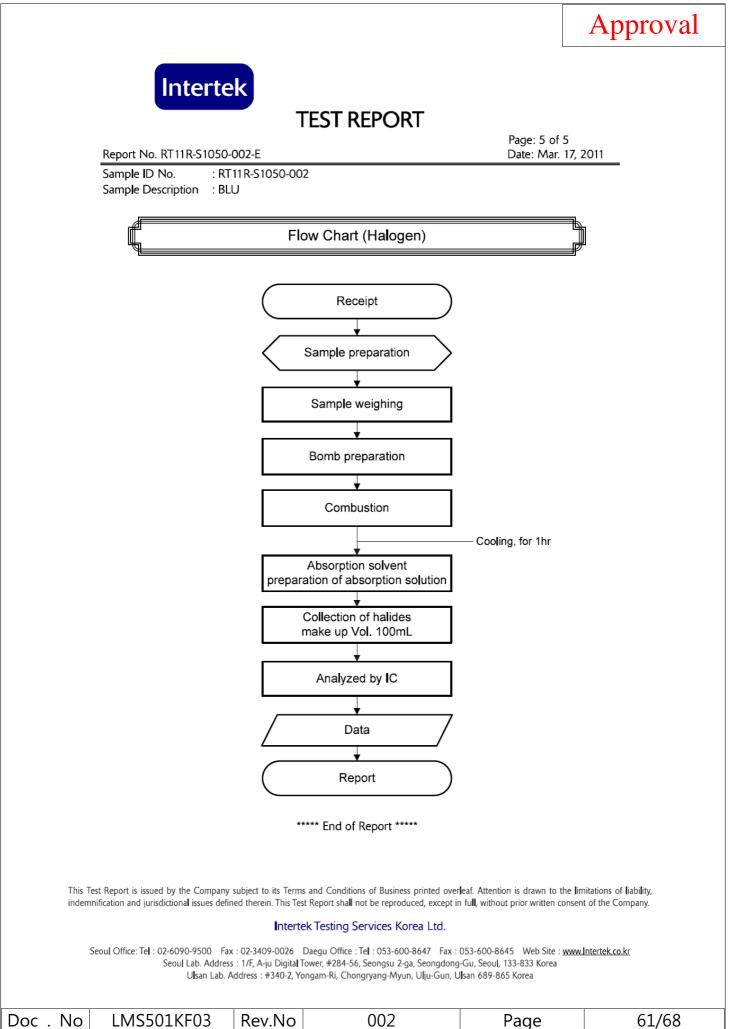
Materia	Acid added for digestion	
Polymers	HNO _{3,} HCI, HF, H ₂ O ₂ , H ₃ BO ₃	
Metals	HNO3, HCI, HF	
Electronics	HNO ₃ , HCI, H ₂ O ₂ , HBF ₄	

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TEST REPORT

Applicant: Samsung Mobile Display Co., Ltd.Address: #508, Seongseong-dong, Seobuk-gu, Cheonan-city, Chungcheongnam-do, 330-300 Korea						
		Page: 1 of 4				
Report No. RT11R-S1050-C	03-E	Date: Mar. 17, 2011				
Sample Description	: The following submitted sample(s) said to be:-					
Name/Type of Product	: Bezel					
Sample ID No.	: RT11R-S1050-003					
Manufacturer/Vender	: Samsung Mobile Display Co., Ltd.					
Sample received Testing Date Testing Environment	: Mar. 15, 2011 : Mar. 15, 2011 ~ Mar. 17, 2011 : Temperature : (24 ± 2) ℃, Humidity : (60 ± 5) % R.H.					
Test Type Test Method(s) Test Result(s)	: RoHS wet chemical analysis : Please see the following page(s). : Please see the following page(s).					

* Note 1 : The test results presented in this report relate only to the object tested.

* Note 2 : This report shall not be reproduced except in full without the written approval of the testing laboratory.

Approved by,

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Jade Jang / Lab. Technical Manager

Authorized by,

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Bo Park / Lab. General Manager

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Report No. RT11R-S1050-003-E

Page: 2 of 4 Date: Mar. 17, 2011

Sample ID No. : RT11R-S1050-003

Sample Description : Bezel

Test Item	Unit	Test Method	MDL	Result
Cadmium (Cd)	mg/kg	With reference to	0.5	N.D.
Lead (Pb)	mg/kg	IEC 62321 Edition 1.0 : 2008, by acid digestion and	5	N.D.
Mercury (Hg)	mg/kg	determined by ICP-OES	2	N.D.
Hexavalent Chromium (Cr ⁶⁺) (For metal)	-	With reference to IEC 62321 Edition 1.0 : 2008, by Spot test	(Threshold of 1 mg/kg)	Negative
Hexavalent Chromium (Cr ⁶⁺) (For metal)	-	With reference to IEC 62321 Edition 1.0 : 2008, by boiling water extraction and determined by UV-VIS Spectrophotometer	(Threshold of 0.02 mg/kg with 50 cm ²)	Negative

Tested by : Nikkie Lee, Leo Kim

Notes : mg/kg = ppm = parts per million

mg/kg with 50 cm² = milligram per kilogram with 50 square centimeter \leq Less than

N.D. = Not detected (<MDL)

MDL = Method detection limit

- Positive = A positive test result indicated the presence of Cr(VI) at the time of testing, equal to or greater than threshold of 1 mg/kg for spot test procedures or 0.02 mg/kg for boiling water extraction procedures with a sample surface area of 50 cm² used. However, it shall not be interpreted as the Cr(VI) concentration in the coating layer of the sample and should not be used as a method detection limit for this qualitative test.
- Negative = A negative test result indicates above positive observation was not found at the time of testing. When the spot test showed a negative result, the boiling water extraction procedure shall be used to verify the result.

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Report No. RT11R-S1050-003-E

Page: 3 of 4 Date: Mar. 17, 2011

Sample ID No. : RT11R-S1050-003 Sample Description : Bezel

* View of sample as received;-



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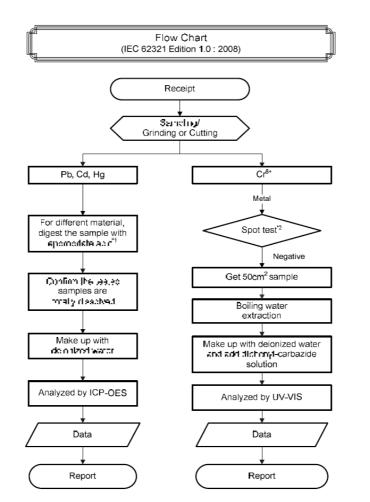
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Page: 4 of 4 Date: Mar. 17, 2011

Report No. RT11R-S1050-003-E

Sample ID No. : RT11R-S1050-003 Sample Description : Bezel



Remarks :

*1 : List of appropriate acid :

Material	Acid added for digestion
Polymers	HNO ₃ , HCl, HF, H ₂ O ₂ , H ₃ BO ₃
Metals	HNO ₃ , HCI, HF
Electronics	HNO ₃ , HCl, H ₂ O ₂ , HBF ₄

*2 : If the result of spot test is positive, Chromium (VI) would be determined as detected. No further analysis is required.

***** End of Report *****

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검사 표준

Approval

1. 검사 조건

1) 검사환경
 가) 온 도 : 23 ± 2℃
 ② 검사거리와 각도

- 가)거 리: 30 ± 5cm
- 나) 각 도 : 상하좌우 30°
- ③ 검사 조도 가) 외관 : 1,000 ~ 1,500 Lux 나) 구동 : 50 ~ 150 Lux

2. 검사 방법(샘플링)

검사수준	시 료 발 취	AQL
일반검사 ㅣ	MIL-STD-105D 계수조정형 1회 샘플링 검사	중결점 : 0.1 경결점 : 0.65

⑦ 중결점 : 제품을 못쓰게 되거나, 제품이 목적으로 하는 실질적인 특성을 저하시켜
 소기의 목적을 달성하지 못하게 하는 결점

② 경결점 : 제품의 각 부품별 기능 및 동작 시 사용상 불안정 하거나 제품의 가치를 저하시키는 결점

③ 결함 적용 영역: 가시영역 (도면확인)

	7	시 영역 외 나시 영역 구동 영역		가시영역외 평가되지 않 Viewing Ar (가시영역) 구동영역 :	낳는다.
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Approval

3. 검사 항목 및 판정 기준

1) 주요 구동 불량 Spec

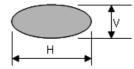
항 목	판정기준	결점구분
1)Disp l ay무	·없을 것	중결점
2)표시이상	·없을 것	중결점
3)Short	·없을 것	중결점
4)Open(B I T)	·없을 것	중결점

2) 외관 검사 Spec

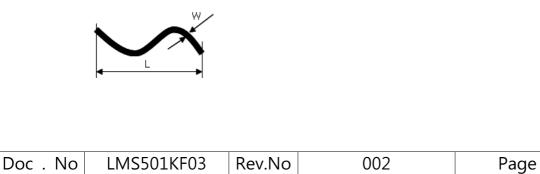
항목	판정기준	결점구분		
	크기 D (mm)	허용 개수 (ea)		
원형 이물 -	D≤0.1	무시	경결점	
	$0.1 < D \le 0.15$	2 (점간 거리 5mm 이상)	95G	
	0.15 <d≤0.2< td=""><td>1</td><td></td></d≤0.2<>	1		
	Width W (mm) , Length L (mm)	허용 개수 (ea)		
선형 이물	W≤0 . 03	3		
	W≤0.05, L≤2.0	2	경결점	
	W≤0.08, L≤1.0	1		
	W>0.08			
	크기 D (mm)	허용 개수 (ea)		
POL기포 / POL찍힘	D≤0.1	무시	경결점	
	0.1 <d≤0.3< td=""><td>3</td><td></td></d≤0.3<>	3		
	Width W (mm), Length L (mm)	허용개수 (ea)		
POL긁힘	W≤0.05	무시	경결점	
	0.05 <w≤0.08, 1.0<l≤5.0<="" td=""><td>1</td><td></td></w≤0.08,>	1		
	최대 허용 개수	3	-	

💥 Remark

- 원형이물, 기포의 지름 : D = [세로(V) + 가로(H)] / 2



- 선형이물, 긁힘의 길이 및 두께



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3) Dot 불량 Spec

항목	판정기준					
84	Dot Type	허 용개 수 (ea)	결점구분			
명점	Random (Red , Blue, Green)	0	경결점			
012	2개 또는 인접한 dot인 경우	0	32A			
	Dark dot	2 (거리 ≥ 10mm)				
암점	2개 인접한 dot인 경우	0	경결점			
	3개 또는 그 이상 인접한 dot인 경우	0				
	최대 허용 개수	2	-			

4) Crack, Chipping, Broken

구분 ACK	발생유형	SPEC			. v	X, Y 정의	
ACK		공통기준	결점구분	- 검사 Point	· ^ ,	184	
	CRACK	없을 것	중결점	TFT & CF		_	
				Glass전체			
- 모서리 FT)	CHIPPING BROKEN	X≤2.5, Y≤1.5 X≤1.5, Y≤2.5 (단, Align mark 침범	경결점		개념의 Depth는 >	에 따라 X,Y 길이 으로 적용함. (,Y 길이 방향 外 영역의 깨짐.	
		없을 것)		6	> v		
	CHIPPING	X≤1.5 Y≤1.0	경결점	م	⊳ Y∳	·	
외 모서리 TFT)	BROKEN	X≤1.5 Y≤0.3	경결점	ہ و		× ₹	
(edge) TFT)	CHIPPING	X≤5.0, Y≤0.5	경결점				
ge) (CF)	BROKEN	X≤5.0, Y≤0.5	경결점			면 4변부이며, 미 DADH 이찌	
ge) (TFT)	BROKEN	X≤5.0, Y≤0.3	경결점	(e 및 PAD무 안곡]범한 영역임.	
PC 본딩부 dge)	CHIPPING BROKEN	X≤5mm Y≤0.4mm (단, FOG PAD 0.2mm이상 침범 시 불량. Vcom 배선 침범 안할 것)	경결점		×↓	× + + + + + + - + - - - - - - - - - - - - -	
	FT) 외 모서리 TFT) edge) TFT) ge) (CF) ge) (TFT) ge) (TFT)	FT) BROKEN BROKEN (HIPPING BROKEN (CF) BROKEN (Ge) (CF) BROKEN (Ge) (TFT) BROKEN (Ge) (TFT) BROKEN	모처리 FT)CHIPPING BROKEN(단, Align mark 침범 없을 것)FT)CHIPPING CHIPPINGX≤1.5 Y≤1.0ISI 모처리 TFT)BROKENX≤1.5 Y≤0.3edge) TFT)CHIPPING BROKENX≤5.0, Y≤0.5ge) (CF)BROKENX≤5.0, Y≤0.5ge) (TFT)BROKENX≤5.0, Y≤0.3ge) (TFT)BROKENX≤5.0, Y≤0.4ge) (TFT)BROKENX≤5.0, Y≤0.3ge) (TFT)BROKENX≤0.4ge) (TFT)BROKENX≤0.4ge) (TFT)BROKENX≤0.4ge) (TFT)BROKE	보처리 FT)CHIPPING BROKEN(단, Align mark 침범 없을 것)경결점FT)CHIPPINGX<1.5 Y<1.0	$ \begin{array}{c} \begin{array}{c} \begin{array}{c} \left(\text{E}, \text{Align} \\ \text{BROKEN} \end{array} \right) & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ \text{mark & ald} \\ alge & 2 \end{array} \right) \end{array} \right) & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ \text{mark & ald} \\ alge & 2 \end{array} \right) \end{array} \right) \\ \begin{array}{c} \begin{array}{c} \left(\text{E}, \text{Align} \\ \text{mark & ald} \\ alge & 2 \end{array} \right) \end{array} & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ \text{mark & ald} \\ alge & 2 \end{array} \right) \end{array} \right) & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ \text{mark & ald} \\ alge & 2 \end{array} \right) \end{array} \right) \\ \begin{array}{c} \begin{array}{c} \left(\text{E}, \text{Align} \\ alge & 2 \end{array} \right) \end{array} & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ mark & ald \\ alge & 2 \end{array} \right) \end{array} \right) & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ mark & ald \\ alge & 2 \end{array} \right) \end{array} \right) \\ \begin{array}{c} \left(\text{E}, \text{Align} \\ \text{FT} \end{array} \right) \end{array} & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ \text{Server} \end{array} \right) \end{array} \right) & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ \text{Server} \end{array} \right) \end{array} \right) \\ \begin{array}{c} \left(\text{Server} \end{array} \right) & \left(\begin{array}{c} \left(\text{E}, \text{Align} \\ \text{Server} \end{array} \right) \end{array} \right) \end{array} & \left(\begin{array}{c} \left(\text{Server} \end{array} \right) \end{array} \right) \\ \begin{array}{c} \left(\text{Server} \end{array} \right) & \left(\begin{array}{c} \left(\text{Server} \end{array} \right) \end{array} \right) \\ \begin{array}{c} \left(\text{Server} \end{array} \right) & \left(\begin{array}{c} \left(\text{Server} \end{array} \right) \end{array} \right) \\ \begin{array}{c} \left(\text{Server} \end{array} \right) & \left(\begin{array}{c} \left(\text{Server} \end{array} \right) \end{array} \right) \\ \begin{array}{c} \left(\text{Server} \end{array} \right) \\ \begin{array}{c} \left(\text{Server} \end{array} \right) & \left(\begin{array}{c} \left(\text{Server} \end{array} \right) \end{array} \right) \\ \begin{array}{c} \left(\text{Server} \end{array} \right) \\ \end{array} \\ \begin{array}{c} \left(\text{Server} \end{array} \right) \\ \end{array} \\ \begin{array}{c} \left(\text{Server} \end{array} \right) \\ \end{array} $ \\ \begin{array}{c} \left(\text{Server} \end{array} \right) \\ \end{array} \\ \begin{array}{c} \left(\text{Server} \end{array} \right) \\ \end{array} \\ \begin{array}{c} \left(\text{Server} \end{array} \right) \\ \end{array} \\ \end{array} \\ \begin{array}{c} \left(\text{Serve} \end{array} \right) \\ \end{array} \end{array} \\	모서리 FT) CHIPPING BROKEN (E, Align mark 침범 없을 것) 경결점 Depth는 > 2°쪽 4 TFT) CHIPPING X<1.5 Y≤1.0 경결점 Depth는 > 2°쪽 4 ISI PARA TFT) CHIPPING X<1.5 Y≤1.0 경결점 Image: Chipping Depthe > 2°쪽 4 BROKEN X<1.5 Y≤0.3 경결점 Image: Chipping Depthe > 2°주 4 Image: Chipping Depthe > 2°주 4 Gedge) TFT) CHIPPING X<1.5 Y≤0.3 경결점 Image: Chipping X<5.0, Y<0.5	